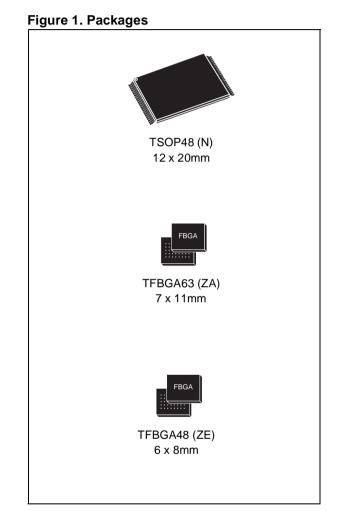


# M29DW323DT M29DW323DB

32 Mbit (4Mb x8 or 2Mb x16, Dual Bank 8:24, Boot Block) 3V Supply Flash Memory

# FEATURES SUMMARY

- SUPPLY VOLTAGE
  - V<sub>CC</sub> = 2.7V to 3.6V for Program, Erase and Read
  - VPP =12V for Fast Program (optional)
- ACCESS TIME: 70, 90ns
- PROGRAMMING TIME
  - 10µs per Byte/Word typical
  - Double Word/ Quadruple Byte Program
- MEMORY BLOCKS
  - Dual Bank Memory Array: 8Mbit+24Mbit
  - Parameter Blocks (Top or Bottom Location)
- DUAL OPERATIONS
  - Read in one bank while Program or Erase in other
- ERASE SUSPEND and RESUME MODES
  - Read and Program another Block during Erase Suspend
- UNLOCK BYPASS PROGRAM COMMAND
  - Faster Production/Batch Programming
- V<sub>PP</sub>/WP PIN for FAST PROGRAM and WRITE PROTECT
- TEMPORARY BLOCK UNPROTECTION MODE
- COMMON FLASH INTERFACE
  - 64 bit Security Code
- EXTENDED MEMORY BLOCK
  - Extra block used as security block or to store additional information
- LOW POWER CONSUMPTION
  - Standby and Automatic Standby
- 100,000 PROGRAM/ERASE CYCLES per BLOCK
- ELECTRONIC SIGNATURE
  - Manufacturer Code: 0020h
  - Top Device Code M29DW323DT: 225Eh
  - Bottom Device Code M29DW323DB: 225Fh



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# M29DW323DT, M29DW323DB

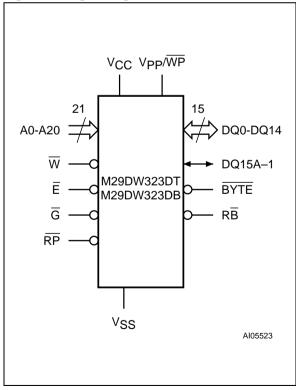
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#### SUMMARY DESCRIPTION

The M29DW323D is a 32 Mbit (4Mb x8 or 2Mb x16) non-volatile memory that can be read, erased and reprogrammed. These operations can be performed using a single low voltage (2.7 to 3.6V) supply. On power-up the memory defaults to its Read mode where it can be read in the same way as a ROM or EPROM.

The device features an asymmetrical block architecture. The M29DW323D has an array of 8 parameter and 63 main blocks and is divided into two Banks, A and B, providing Dual Bank operations. While programming or erasing in Bank A, read operations are possible in Bank B and vice versa. Only one bank at a time is allowed to be in program or erase mode. The bank architecture is summarized in Table 2. M29DW323DT locates the Parameter Blocks at the top of the memory address space while the M29DW323DB locates the Parameter Blocks starting from the bottom.

M29DW323D has an extra 32 KWord (x16 mode) or 64 KByte (x8 mode) block, the Extended Block, that can be accessed using a dedicated command. The Extended Block can be protected and so is useful for storing security information. How-



# Figure 2. Logic Diagram

ever the protection is irreversible, once protected the protection cannot be undone.

Each block can be erased independently so it is possible to preserve valid data while old data is erased. The blocks can be protected to prevent accidental Program or Erase commands from modifying the memory. Program and Erase commands are written to the Command Interface of the memory. An on-chip Program/Erase Controller simplifies the process of programming or erasing the memory by taking care of all of the special operations that are required to update the memory contents. The end of a program or erase operation can be detected and any error conditions identified. The command set required to control the memory is consistent with JEDEC standards.

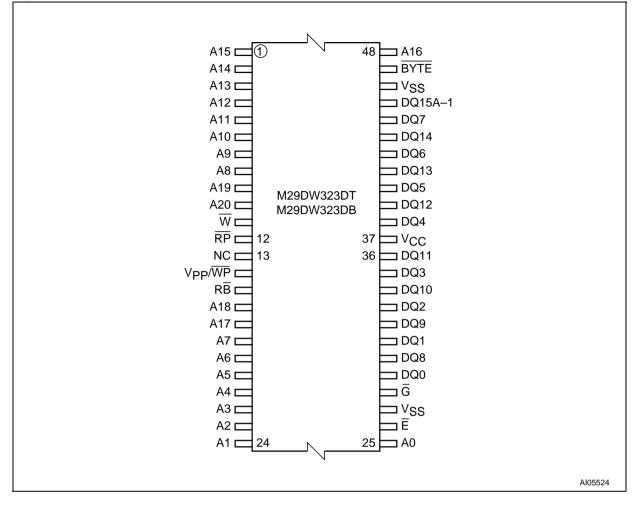
Chip Enable, Output Enable and Write Enable signals control the bus operation of the memory. They allow simple connection to most microprocessors, often without additional logic.

The memory is offered in TSOP48 (12x20mm), TFBGA63 (7x11mm, 0.8mm pitch) and TFBGA48 (6x8mm, 0.8mm pitch) packages. The memory is supplied with all the bits erased (set to '1').

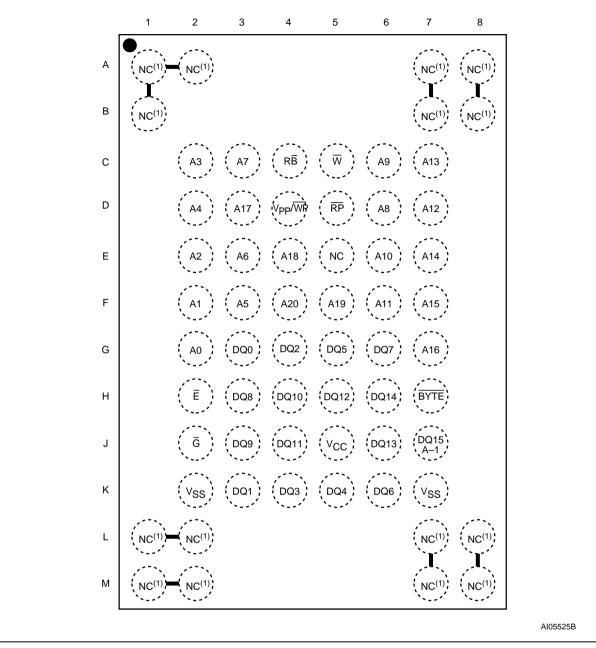
A0-A20	Address Inputs						
DQ0-DQ7	Data Inputs/Outputs						
DQ8-DQ14	Data Inputs/Outputs						
DQ15A-1	Data Input/Output or Address Input						
Ē	Chip Enable						
G	Output Enable						
W	Write Enable						
RP	Reset/Block Temporary Unprotect						
RB	Ready/Busy Output						
BYTE	Byte/Word Organization Select						
V <sub>CC</sub>	Supply Voltage						
V <sub>PP</sub> /WP	V <sub>PP</sub> /Write Protect						
V <sub>SS</sub>	Ground						
NC	Not Connected Internally						

#### Table 1. Signal Names

## Figure 3. TSOP Connections

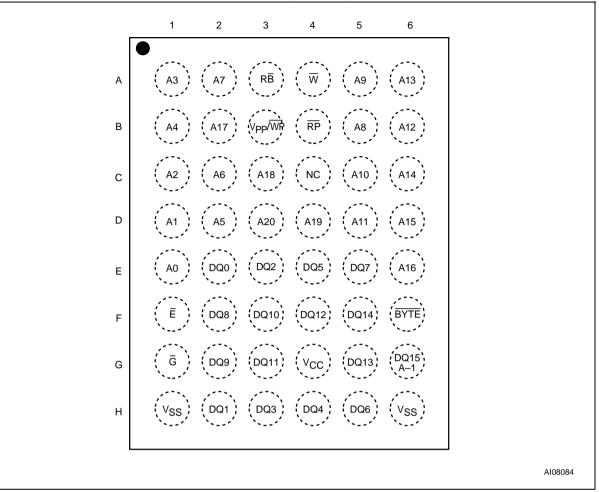






Note: 1. Balls are shorted together via the substrate but not connected to the die.

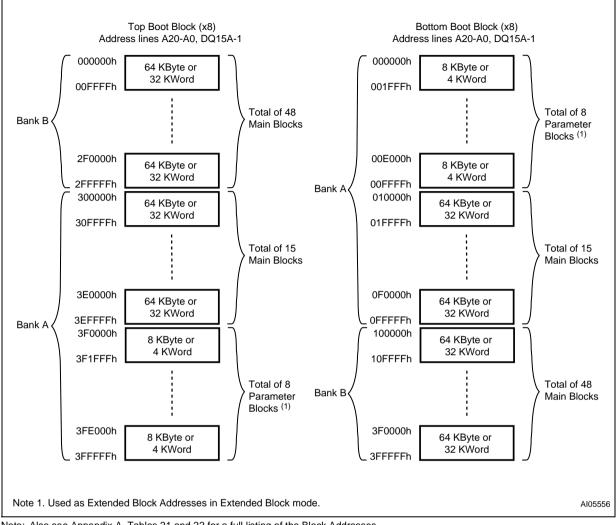
# Figure 5. TFBGA48 Connections (Top view through package)



#### **Table 2. Bank Architecture**

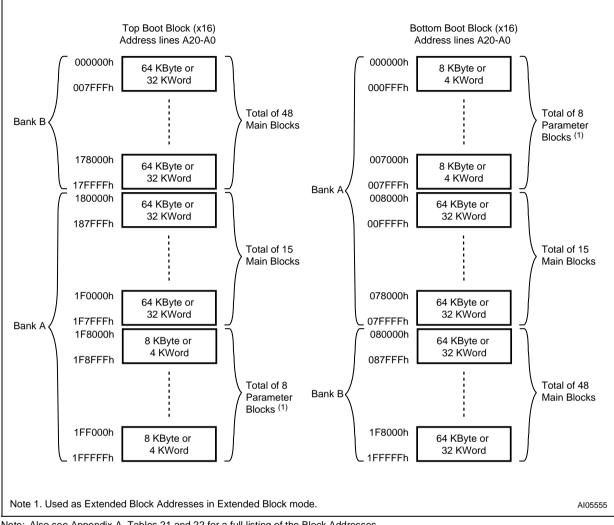
		Paran	neter Blocks	Main Blocks			
Bank	Bank Size			No. of Blocks	Block Size		
A	8 Mbit	8	8KByte/ 4 KWord	15	64KByte/ 32 KWord		
В	24 Mbit	-		48	64KByte/ 32 KWord		

#### Figure 6. Block Addresses (x8)



Note: Also see Appendix A, Tables 21 and 22 for a full listing of the Block Addresses.

# Figure 7. Block Addresses (x16)



Note: Also see Appendix A, Tables 21 and 22 for a full listing of the Block Addresses.

## SIGNAL DESCRIPTIONS

See Figure 2, Logic Diagram, and Table 1, Signal Names, for a brief overview of the signals connected to this device.

Address Inputs (A0-A20). The Address Inputs select the cells in the memory array to access during Bus Read operations. During Bus Write operations they control the commands sent to the Command Interface of the Program/Erase Controller.

**Data Inputs/Outputs (DQ0-DQ7).** The Data I/O outputs the data stored at the selected address during a Bus Read operation. During Bus Write operations they represent the commands sent to the Command Interface of the Program/Erase Controller.

**Data Inputs/Outputs (DQ8-DQ14).** The Data I/O outputs the data stored at the selected address during a Bus Read operation when BYTE is High,  $V_{IH}$ . When BYTE is Low,  $V_{IL}$ , these pins are not used and are high impedance. During Bus Write operations the Command Register does not use these bits. When reading the Status Register these bits should be ignored.

**Data Input/Output or Address Input (DQ15A–1).** When  $\overline{\text{BYTE}}$  is High, V<sub>IH</sub>, this pin behaves as a <u>Data</u> Input/Output pin (as DQ8-DQ14). When  $\overline{\text{BYTE}}$  is Low, V<sub>IL</sub>, this pin behaves as an address pin; DQ15A–1 Low will select the LSB of the addressed Word, DQ15A–1 High will select the MSB. Throughout the text consider references to the Data Input/Output to include this pin when  $\overline{\text{BYTE}}$  is High and references to the Address Inputs to in-

stated explicitly otherwise. **Chip Enable (\overline{E}).** The Chip Enable,  $\overline{E}$ , activates the memory, allowing Bus Read and Bus Write operations to be performed. When Chip Enable is High, V<sub>IH</sub>, all other pins are ignored.

clude this pin when BYTE is Low except when

**Output Enable** ( $\overline{G}$ ). The Output Enable,  $\overline{G}$ , controls the Bus Read operation of the memory.

Write Enable ( $\overline{W}$ ). The Write Enable,  $\overline{W}$ , controls the Bus Write operation of the memory's Command Interface.

**Vpp/Write Protect (Vpp/WP).** The Vpp/Write Protect pin provides two functions. The Vpp function allows the memory to use an external high voltage power supply to reduce the time required for Program operations. This is achieved by bypassing the unlock cycles and/or using the Double Word or Quadruple Byte Program commands. The Write Protect function provides a hardware method of protecting the two outermost boot blocks.

When  $V_{PP}$ /Write Protect is Low,  $V_{IL}$ , the memory protects the two outermost boot blocks; Program

and Erase operations in these blocks are ignored while  $V_{PP}$ /Write Protect is Low, even when  $\overline{RP}$  is at  $V_{ID}$ .

When  $V_{PP}$ /Write Protect is High,  $V_{IH}$ , the memory reverts to the previous protection status of the two outermost boot blocks. Program and Erase operations can now modify the data in these blocks unless the blocks are protected using Block Protection.

When  $V_{PP}$ /Write Protect is raised to  $V_{PP}$  the memory automatically enters the Unlock Bypass mode. When  $V_{PP}$ /Write Protect returns to  $V_{IH}$  or  $V_{IL}$  normal operation resumes. During Unlock Bypass Program operations the memory draws  $I_{PP}$  from the pin to supply the programming circuits. See the description of the Unlock Bypass command in the Command Interface section. The transitions from  $V_{IH}$  to  $V_{PP}$  and from  $V_{PP}$  to  $V_{IH}$  must be slower than  $t_{VHVPP}$ , see Figure 16.

Never raise  $V_{PP}$ /Write Protect to  $V_{PP}$  from any mode except Read mode, otherwise the memory may be left in an indeterminate state.

The V<sub>PP</sub>/Write Protect pin must not be left floating or unconnected or the device may become unreliable. A  $0.1\mu$ F capacitor should be connected between the V<sub>PP</sub>/Write Protect pin and the V<sub>SS</sub> Ground pin to decouple the current surges from the power supply. The PCB track widths must be sufficient to carry the currents required during Unlock Bypass Program, I<sub>PP</sub>.

**Reset/Block Temporary Unprotect (\overline{RP}).** The Reset/Block Temporary Unprotect pin can be used to apply a Hardware Reset to the memory or to temporarily unprotect all Blocks that have been protected.

Note that if  $V_{PP}/\overline{WP}$  is at  $V_{IL}$ , then the two outermost boot blocks will remain protected even if RP is at  $V_{ID}$ .

A Hardware Reset is achieved by holding Reset/ Block Temporary Unprotect Low,  $V_{IL}$ , for at least  $t_{PLPX}$ . After Reset/Block Temporary Unprotect goes High,  $V_{IH}$ , the memory will be ready for Bus Read and Bus Write operations after  $t_{PHEL}$  or  $t_{RHEL}$ , whichever occurs last. See the Ready/Busy Output section, Table 16 and Figure 15, Reset/ Temporary Unprotect AC Characteristics for more details.

Holding  $\overline{RP}$  at V<sub>ID</sub> will temporarily unprotect the protected Blocks in the memory. Program and Erase operations on all blocks will be possible. The transition from V<sub>IH</sub> to V<sub>ID</sub> must be slower than t<sub>PHPHH</sub>.

**Ready/Busy Output (RB).** The Ready/Busy pin is an open-drain output that can be used to identify when the device is performing a Program or Erase operation. During Program or Erase operations

Ready/Busy is Low,  $V_{OL}.\ Ready/Busy$  is high-impedance during Read mode, Auto Select mode and Erase Suspend mode.

After a Hardware Reset, Bus Read and Bus Write operations cannot begin until Ready/Busy becomes high-impedance. See Table 16 and Figure 15, Reset/Temporary Unprotect AC Characteristics.

The use of an open-drain output allows the Ready/ Busy pins from several memories to be connected to a single pull-up resistor. A Low will then indicate that one, or more, of the memories is busy.

**Byte/Word Organization Select (BYTE).** The Byte/Word Organization Select pin is used to switch between the x8 and x16 Bus modes of the memory. When Byte/Word Organization Select is Low,  $V_{IL}$ , the memory is in x8 mode, when it is High,  $V_{IH}$ , the memory is in x16 mode.

 $V_{CC}$  Supply Voltage (2.7V to 3.6V).  $V_{CC}$  provides the power supply for all operations (Read, Program and Erase).

The Command Interface is disabled when the V<sub>CC</sub> Supply Voltage is less than the Lockout Voltage, V<sub>LKO</sub>. This prevents Bus Write operations from accidentally damaging the data during power up, power down and power surges. If the Program/ Erase Controller is programming or erasing during this time then the operation aborts and the memory contents being altered will be invalid.

A 0.1 $\mu$ F capacitor should be connected between the V<sub>CC</sub> Supply Voltage pin and the V<sub>SS</sub> Ground pin to decouple the current surges from the power supply. The PCB track widths must be sufficient to carry the currents required during Program and Erase operations, I<sub>CC3</sub>.

 $V_{SS}$  Ground.  $V_{SS}$  is the reference for all voltage measurements. The device features two  $V_{SS}$  pins which must be both connected to the system ground.

### **BUS OPERATIONS**

There are five standard bus operations that control the device. These are Bus Read, Bus Write, Output Disable, Standby and Automatic Standby.

The Dual Bank architecture of the M29DW323 allows read/write operations in Bank A, while read operations are being executed in Bank B or vice versa. Write operations are only allowed in one bank at a time.

See Tables 3 and 4, Bus Operations, for a summary. Typically glitches of less than 5ns on Chip Enable or Write Enable are ignored by the memory and do not affect bus operations.

**Bus Read.** Bus Read operations read from the memory cells, or specific registers in the Command Interface. A valid Bus Read operation involves setting the desired address on the Address Inputs, applying a Low signal,  $V_{IL}$ , to Chip Enable and Output Enable and keeping Write Enable High,  $V_{IH}$ . The Data Inputs/Outputs will output the value, see Figure 12, Read Mode AC Waveforms, and Table 13, Read AC Characteristics, for details of when the output becomes valid.

**Bus Write.** Bus Write operations write to the Command Interface. A valid Bus Write operation begins by setting the desired address on the Address Inputs. The Address Inputs are latched by the Command Interface on the falling edge of Chip Enable or Write Enable, whichever occurs last. The Data Inputs/Outputs are latched by the Command Interface on the rising edge of Chip Enable or Write Enable, whichever occurs first. Output Enable must remain High,  $V_{IH}$ , during the whole Bus Write operation. See Figures 13 and 14, Write AC Waveforms, and Tables 14 and 15, Write AC Characteristics, for details of the timing requirements.

**Output Disable.** The Data Inputs/Outputs are in the high impedance state when Output Enable is High,  $V_{\text{IH}}$ .

**Standby.** When Chip Enable is High,  $V_{IH}$ , the memory enters Standby mode and the Data Inputs/Outputs pins are placed in the high-imped-

ance state. To reduce the Supply Current to the Standby Supply Current,  $I_{CC2}$ , Chip Enable should be held within  $V_{CC} \pm 0.2V$ . For the Standby current level see Table 12, DC Characteristics.

During program or erase operations the memory will continue to use the Program/Erase Supply Current,  $I_{CC3}$ , for Program or Erase operations until the operation completes.

Automatic Standby. If CMOS levels ( $V_{CC} \pm 0.2V$ ) are used to drive the bus and the bus is inactive for 300ns or more the memory enters Automatic Standby where the internal Supply Current is reduced to the Standby Supply Current,  $I_{CC2}$ . The Data Inputs/Outputs will still output data if a Bus Read operation is in progress.

#### **Special Bus Operations**

Additional bus operations can be performed to read the Electronic Signature and also to apply and remove Block Protection. These bus operations are intended for use by programming equipment and are not usually used in applications. They require  $V_{ID}$  to be applied to some pins.

**Electronic Signature.** The memory has two codes, the manufacturer code and the device code, that can be read to identify the memory. These codes can be read by applying the signals listed in Tables 3 and 4, Bus Operations.

**Block Protect and Chip Unprotect.** Groups of blocks can be protected against accidental Program or Erase. The Protection Groups are shown in Appendix A, Tables 21 and 22, Block Addresses. The whole chip can be unprotected to allow the data inside the blocks to be changed.

The V<sub>PP</sub>/Write Protect pin can be used to protect the two outermost boot blocks. When V<sub>PP</sub>/Write Protect is at V<sub>IL</sub> the two outermost boot blocks are protected and remain protected regardless of the Block Protection Status or the Reset/Block Temporary Unprotect pin status.

Block Protect and Chip Unprotect operations are described in Appendix D.

Oneretien	EG		w	Address Inputs	Data Inputs/Outputs			
Operation	<b>–</b>	G	vv	DQ15A-1, A0-A20	DQ14-DQ8	DQ7-DQ0		
Bus Read	VIL	VIL	VIH	Cell Address	Hi-Z	Data Output		
Bus Write	VIL	VIH	VIL	Command Address	Hi-Z	Data Input		
Output Disable	Х	VIH	VIH	Х	Hi-Z H			
Standby	VIH	Х	Х	Х	Hi-Z	Hi-Z		
Read Manufacturer Code	V <sub>IL</sub>	V <sub>IL</sub>	V <sub>IH</sub>	$\begin{array}{l} A0 = V_{IL},  A1 = V_{IL},  A9 = V_{ID}, \\ Others  V_{IL}  or  V_{IH} \end{array}$	Hi-Z	20h		
Read Device Code	V <sub>IL</sub>	V <sub>IL</sub>	V <sub>IH</sub>		Hi-Z	5Eh (M29DW323DT) 5Fh (M29DW323DB)		
Extended Memory Block Verify Code			V <sub>IH</sub>	$      A0 = V_{IH}, A1 = V_{IH}, A6 = V_{IL}, \\       A9 = V_{ID}, Others V_{IL} \ or \ V_{IH} $	Hi-Z	81h (factory locked) 01h (not factory locked)		

# Table 3. Bus Operations, $\overline{\text{BYTE}} = V_{\text{IL}}$

Note:  $X = V_{IL}$  or  $V_{IH}$ .

# Table 4. Bus Operations, $\overline{\text{BYTE}} = V_{\text{IH}}$

Operation	Operation E G W		Address Inputs A0-A20	Data Inputs/Outputs DQ15A-1, DQ14-DQ0	
Bus Read	VIL	VIL	VIH	Cell Address	Data Output
Bus Write	VIL	VIH	VIL	Command Address	Data Input
Output Disable	Х	VIH	VIH	Х	Hi-Z
Standby	VIH	Х	Х	Х	Hi-Z
Read Manufacturer Code	VIL	VIL	VIH	$\begin{array}{l} A0 = V_{IL},  A1 = V_{IL},  A9 = V_{ID}, \\ Others  V_{IL}  or  V_{IH} \end{array}$	0020h
Read Device Code	ad Device Code $V_{IL}$ $V_{IL}$ $V_{IH}$ $A0 = V_{IH}$ , $A1 = V_{IL}$ , Others $V_{IL}$ or $V_{IH}$		$\begin{array}{l} A0 = V_{IH}, \ A1 = V_{IL}, \ A9 = V_{ID}, \\ Others \ V_{IL} \ or \ V_{IH} \end{array}$	225Eh (M29DW323DT) 225Fh (M29DW323DB)	
		$\begin{array}{l} A0 = V_{IH},  A1 = V_{IH},  A6 = V_{IL}, \\ A9 = V_{ID},  Others  V_{IL}  or  V_{IH} \end{array}$	81h (factory locked) 01h (not factory locked)		

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Note:  $X = V_{IL}$  or  $V_{IH}$ .

## **COMMAND INTERFACE**

All Bus Write operations to the memory are interpreted by the Command Interface. Commands consist of one or more sequential Bus Write operations. Failure to observe a valid sequence of Bus Write operations will result in the memory returning to Read mode. The long command sequences are imposed to maximize data security.

The address used for the commands changes depending on whether the memory is in 16-bit or 8bit mode. See either Table 5, or 6, depending on the configuration that is being used, for a summary of the commands.

#### Read/Reset Command

The Read/Reset command returns the memory to its Read mode where it behaves like a ROM or EPROM. It also resets the errors in the Status Register. Either one or three Bus Write operations can be used to issue the Read/Reset command.

The Read/Reset command can be issued, between Bus Write cycles before the start of a program or erase operation, to return the device to read mode. If the Read/Reset command is issued during the timeout of a Block erase operation then the memory will take up to 10µs to abort. During the abort period no valid data can be read from the memory. The Read/Reset command will not abort an Erase operation when issued while in Erase Suspend.

#### Auto Select Command

The Auto Select command is used to read the Manufacturer Code, the Device Code, the Block Protection Status and the Extended Memory Block Verify Code. It can be addressed to either Bank. Three consecutive Bus Write operations are required to issue the Auto Select command. The final Write cycle must be addressed to one of the Banks. Once the Auto Select command is issued Bus Read operations to the Bank where the command was issued output the Auto Select data. Bus Read operations to the other Bank will output the contents of the memory array. The memory remains in Auto Select mode until a Read/Reset or CFI Query command is issued.

In Auto Select mode the Manufacturer Code can be read using a Bus Read operation with  $A0 = V_{IL}$ and  $A1 = V_{IL}$  and A19-A20 = Bank Address. The other address bits may be set to either  $V_{IL}$  or  $V_{IH}$ .

The Device Code can be read using a Bus Read operation with  $A0 = V_{IH}$  and  $A1 = V_{IL}$  and A19-A20 = Bank Address. The other address bits may be set to either  $V_{IL}$  or  $V_{IH}$ .

The Block Protection Status of each block can be read using a Bus Read operation with  $A0 = V_{IL}$ ,  $A1 = V_{IH}$ , A19-A20 = Bank Address and A12-A17 specifying the address of the block inside the Bank. The other address bits may be set to either

 $V_{IL} \mbox{ or } V_{IH}.$  If the addressed block is protected then 01h is output on Data Inputs/Outputs DQ0-DQ7, otherwise 00h is output.

## Read CFI Query Command

The Read CFI Query Command is used to read data from the Common Flash Interface (CFI) Memory Area. This command is valid when the device is in the Read Array mode, or when the device is in Autoselected mode.

One Bus Write cycle is required to issue the Read CFI Query Command. Once the command is issued subsequent Bus Read operations read from the Common Flash Interface Memory Area.

The Read/Reset command must be issued to return the device to the previous mode (the Read Array mode or Autoselected mode). A second Read/ Reset command would be needed if the device is to be put in the Read Array mode from Autoselected mode.

See Appendix B, Tables 23, 24, 25, 26, 27 and 28 for details on the information contained in the Common Flash Interface (CFI) memory area.

# Program Command

The Program command can be used to program a value to one address in the memory array at a time. The command requires four Bus Write operations, the final write operation latches the address and data, and starts the Program/Erase Controller.

If the address falls in a protected block then the Program command is ignored, the data remains unchanged. The Status Register is never read and no error condition is given.

During the program operation the memory will ignore all commands. It is not possible to issue any command to abort or pause the operation. After programming has started, Bus Read operations in the Bank being programmed output the Status Register content, while Bus Read operations to the other Bank output the contents of the memory array. See the section on the Status Register for more details. Typical program times are given in Table 7.

After the program operation has completed the memory will return to the Read mode, unless an error has occurred. When an error occurs Bus Read operations to the Bank where the command was issued will continue to output the Status Register. A Read/Reset command must be issued to reset the error condition and return to Read mode.

Note that the Program command cannot change a bit set at '0' back to '1'. One of the Erase Commands must be used to set all the bits in a block or in the whole memory from '0' to '1'.

## **Fast Program Commands**

There are two Fast Program commands available to improve the programming throughput, by writing several adjacent words or bytes in parallel. The Quadruple Byte Program command is available for x8 operations, while the Double Word Program command is available for x16 operations.

**Quadruple Byte Program Command.** The Quadruple Byte Program command is used to write a page of four adjacent Bytes in parallel. The four bytes must differ only for addresses A0, DQ15A-1. Five bus write cycles are necessary to issue the Quadruple Byte Program command.

- The first bus cycle sets up the Quadruple Byte Program Command.
- The second bus cycle latches the Address and the Data of the first byte to be written.
- The third bus cycle latches the Address and the Data of the second byte to be written.
- The fourth bus cycle latches the Address and the Data of the third byte to be written.
- The fifth bus cycle latches the Address and the Data of the fourth byte to be written and starts the Program/Erase Controller.

**Double Word Program Command.** The Double Word Program command is used to write a page of two adjacent words in parallel. The two words must differ only for the address A0.

Three bus write cycles are necessary to issue the Double Word Program command.

- The first bus cycle sets up the Double Word Program Command.
- The second bus cycle latches the Address and the Data of the first word to be written.
- The third bus cycle latches the Address and the Data of the second word to be written and starts the Program/Erase Controller.

Only one bank can be programmed at any one time. The other bank must be in Read mode or Erase Suspend.

Programming should not be attempted when  $V_{PP}$  is not at  $V_{PPH}$ .

After programming has started, Bus Read operations in the Bank being programmed output the Status Register content, while Bus Read operations to the other Bank output the contents of the memory array.

After the program operation has completed the memory will return to the Read mode, unless an error has occurred. When an error occurs Bus Read operations to the Bank where the command was issued will continue to output the Status Register. A Read/Reset command must be issued to reset the error condition and return to Read mode. Note that the Fast Program commands cannot change a bit set at '0' back to '1'. One of the Erase Commands must be used to set all the bits in a block or in the whole memory from '0' to '1'.

Typical Program times are given in Table 7, Program, Erase Times and Program/Erase Endurance Cycles.

#### **Unlock Bypass Command**

The Unlock Bypass command is used in conjunction with the Unlock Bypass Program command to program the memory faster than with the standard program commands. When the cycle time to the device is long (as with some EPROM programmers) considerable time saving can be made by using these commands. Three Bus Write operations are required to issue the Unlock Bypass command.

Once the Unlock Bypass command has been issued the bank enters Unlock Bypass mode. The Unlock Bypass Program command can then be issued to program addresses within the bank, or the Unlock Bypass Reset command can be issued to return the bank to Read mode. In Unlock Bypass mode the memory can be read as if in Read mode.

When  $V_{PP}$  is applied to the  $V_{PP}$ /Write Protect pin the memory automatically enters the Unlock Bypass mode and the Unlock Bypass Program command can be issued immediately.

### **Unlock Bypass Program Command**

The Unlock Bypass Program command can be used to program one address in the memory array at a time. The command requires two Bus Write operations, the final write operation latches the address and data, and starts the Program/Erase Controller.

The Program operation using the Unlock Bypass Program command behaves identically to the Program operation using the Program command. The operation cannot be aborted, a Bus Read operation to the Bank where the command was issued outputs the Status Register. See the Program command for details on the behavior.

#### Unlock Bypass Reset Command

The Unlock Bypass Reset command can be used to return to Read/Reset mode from Unlock Bypass Mode. Two Bus Write operations are required to issue the Unlock Bypass Reset command. Read/ Reset command does not exit from Unlock Bypass Mode.

#### **Chip Erase Command**

The Chip Erase command can be used to erase the entire chip. Six Bus Write operations are required to issue the Chip Erase Command and start the Program/Erase Controller.

If any blocks are protected then these are ignored and all the other blocks are erased. If all of the



blocks are protected the Chip Erase operation appears to start but will terminate within about 100µs, leaving the data unchanged. No error condition is given when protected blocks are ignored.

During the erase operation the memory will ignore all commands, including the Erase Suspend command. It is not possible to issue any command to abort the operation. Typical chip erase times are given in Table 7. All Bus Read operations during the Chip Erase operation will output the Status Register on the Data Inputs/Outputs. See the section on the Status Register for more details.

After the Chip Erase operation has completed the memory will return to the Read Mode, unless an error has occurred. When an error occurs the memory will continue to output the Status Register. A Read/Reset command must be issued to reset the error condition and return to Read Mode.

The Chip Erase Command sets all of the bits in unprotected blocks of the memory to '1'. All previous data is lost.

### **Block Erase Command**

The Block Erase command can be used to erase a list of one or more blocks in a Bank. It sets all of the bits in the unprotected selected blocks to '1'. All previous data in the selected blocks is lost.

Six Bus Write operations are required to select the first block in the list. Each additional block in the list can be selected by repeating the sixth Bus Write operation using the address of the additional block. All blocks must belong to the same Bank; if a block belonging to the other Bank is given it will not be erased. The Block Erase operation starts the Program/Erase Controller after a time-out period of 50µs after the last Bus Write operation. Once the Program/Erase Controller starts it is not possible to select any more blocks. Each additional block must therefore be selected within 50µs of the last block. The 50µs timer restarts when an additional block is selected. After the sixth Bus Write operation a Bus Read operation within the same Bank will output the Status Register. See the Status Register section for details on how to identify if the Program/Erase Controller has started the Block Erase operation.

If any selected blocks are protected then these are ignored and all the other selected blocks are erased. If all of the selected blocks are protected the Block Erase operation appears to start but will terminate within about  $100\mu$ s, leaving the data unchanged. No error condition is given when protected blocks are ignored.

During the Block Erase operation the memory will ignore all commands except the Erase Suspend command and the Read/Reset command which is only accepted during the 50µs time-out period. Typical block erase times are given in Table 7.

After the Erase operation has started all Bus Read operations to the Bank being erased will output the Status Register on the Data Inputs/Outputs. See the section on the Status Register for more details.

After the Block Erase operation has completed the memory will return to the Read Mode, unless an error has occurred. When an error occurs Bus Read operations to the Bank where the command was issued will continue to output the Status Register. A Read/Reset command must be issued to reset the error condition and return to Read mode.

### **Erase Suspend Command**

The Erase Suspend Command may be used to temporarily suspend a Block Erase operation and return the memory to Read mode. The command requires one Bus Write operation.

The Program/Erase Controller will suspend within the Erase Suspend Latency time of the Erase Suspend Command being issued. Once the Program/ Erase Controller has stopped the memory will be set to Read mode and the Erase will be suspended. If the Erase Suspend command is issued during the period when the memory is waiting for an additional block (before the Program/Erase Controller starts) then the Erase is suspended immediately and will start immediately when the Erase Resume Command is issued. It is not possible to select any further blocks to erase after the Erase Resume.

During Erase Suspend it is possible to Read and Program cells in blocks that are not being erased; both Read and Program operations behave as normal on these blocks. If any attempt is made to program in a protected block or in the suspended block then the Program command is ignored and the data remains unchanged. The Status Register is not read and no error condition is given. Reading from blocks that are being erased will output the Status Register.

It is also possible to issue the Auto Select, Read CFI Query and Unlock Bypass commands during an Erase Suspend. The Read/Reset command must be issued to return the device to Read Array mode before the Resume command will be accepted.

During Erase Suspend a Bus Read operation to the Extended Block will output the Extended Block data.

#### **Erase Resume Command**

The Erase Resume command must be used to restart the Program/Erase Controller after an Erase Suspend. The device must be in Read Array mode before the Resume command will be accepted. An erase can be suspended and resumed more than once.

#### **Enter Extended Block Command**

The M29DW323D has an extra 64KByte block (Extended Block) that can only be accessed using the Enter Extended Block command. Three Bus write cycles are required to issue the Extended Block command. Once the command has been issued the device enters Extended Block mode where all Bus Read or Program operations to the Boot Block addresses access the Extended Block. The Extended Block (with the same address as the boot block) cannot be erased, and can be treated as one-time programmable (OTP) memory. In Extended Block mode the Boot Blocks are not accessible. In Extended Block mode dual operations are possible, with the Extended Block mapped in Bank A. When in Extended Block mode, Erase Commands in Bank A are not allowed.

To exit from the Extended Block mode the Exit Extended Block command must be issued.

The Extended Block can be protected, however once protected the protection cannot be undone.

#### **Exit Extended Block Command**

The Exit Extended Block command is used to exit from the Extended Block mode and return the device to Read mode. Four Bus Write operations are required to issue the command.

#### **Block Protect and Chip Unprotect Commands**

Groups of blocks can be protected against accidental Program or Erase. The Protection Groups are shown in Appendix A, Tables 21 and 22, Block Addresses. The whole chip can be unprotected to allow the data inside the blocks to be changed.

Block Protect and Chip Unprotect operations are described in Appendix D.

	Length					Bus	Write (	Operati	ons				
Command		1st		2nd		3rd		4th		5th		61	th
	Ľ	Addr	Data	Addr	Data	Addr	Data	Addr	Data	Addr	Data	Addr	Data
Read/Reset	1	Х	F0										
Reau/Reset	3	555	AA	2AA	55	Х	F0						
Auto Select	3	555	AA	2AA	55	(BKA) 555	90						
Program	4	555	AA	2AA	55	555	A0	PA	PD				
Double Word Program	3	555	50	PA0	PD0	PA1	PD1						
Unlock Bypass	3	555	AA	2AA	55	555	20						
Unlock Bypass Program	2	х	A0	PA	PD								
Unlock Bypass Reset	2	Х	90	Х	00								
Chip Erase	6	555	AA	2AA	55	555	80	555	AA	2AA	55	555	10
Block Erase	6+	555	AA	2AA	55	555	80	555	AA	2AA	55	BA	30
Erase Suspend	1	BKA	B0										
Erase Resume	1	BKA	30										
Read CFI Query	1	55	98										
Enter Extended Block	3	555	AA	2AA	55	555	88						
Exit Extended Block	4	555	AA	2AA	55	555	90	Х	00				

Table 5. Commands, 16-bit mode, BYTE = VIH

Note: X Don't Care, PA Program Address, PD Program Data, BA Any address in the Block, BKA Bank Address. All values in the table are in hexadecimal.

The Command Interface only uses A–1, A0-A10 and DQ0-DQ7 to verify the commands; A11-A20, DQ8-DQ14 and DQ15 are Don't Care. DQ15A–1 is A–1 when  $\overline{\text{BYTE}}$  is V<sub>IL</sub> or DQ15 when  $\overline{\text{BYTE}}$  is V<sub>IL</sub>.

	ء					Bus V	Vrite O	peratio	ns				
Command	Length	1st		2nd		3rd		4th		5th		6	th
	Ľ	Add	Data	Add	Data	Add	Data	Add	Data	Add	Data	Add	Data
Dood/Dooot	1	Х	F0										
Read/Reset	3	AAA	AA	555	55	Х	F0						
Auto Select	3	AAA	AA	555	55	(BKA) AAA	90						
Program	4	AAA	AA	555	55	AAA	A0	PA	PD				
Quadruple Byte Program	5	AAA	55	PA0	PD0	PA1	PD1	PA2	PD2	PA3	PD3		
Unlock Bypass	3	AAA	AA	555	55	AAA	20						
Unlock Bypass Program	2	Х	A0	PA	PD								
Unlock Bypass Reset	2	Х	90	Х	00								
Chip Erase	6	AAA	AA	555	55	AAA	80	AAA	AA	555	55	AAA	10
Block Erase	6+	AAA	AA	555	55	AAA	80	AAA	AA	555	55	BA	30
Erase Suspend	1	BKA	B0										
Erase Resume	1	BKA	30										
Read CFI Query	1	AA	98										
Enter Extended Block	3	AAA	AA	555	55	AAA	88						
Exit Extended Block	4	AAA	AA	555	55	AAA	90	Х	00				

# Table 6. Commands, 8-bit mode, $\overline{\text{BYTE}} = V_{\text{IL}}$

Note: X Don't Care, PA Program Address, PD Program Data, BA Any address in the Block. All values in the table are in hexadecimal. The Command Interface only uses A–1, A0-A10 and DQ0-DQ7 to verify the commands; A11-A20, DQ8-DQ14 and DQ15 are Don't Care. DQ15A–1 is A–1 when BYTE is V<sub>IL</sub> or DQ15 when BYTE is V<sub>IH</sub>.

#### Table 7. Program, Erase Times and Program, Erase Endurance Cycles

Parameter	Min	Typ <sup>(1, 2)</sup>	Max <sup>(2)</sup>	Unit
Chip Erase		40	200 <sup>(3)</sup>	S
Block Erase (64 KBytes)		0.8	6 <sup>(3)</sup>	S
Erase Suspend Latency Time			50 <sup>(4)</sup>	μs
Program (Byte or Word)		10	200 <sup>(4)</sup>	μs
Double Word Program (Byte or Word)		10	200 <sup>(3)</sup>	μs
Chip Program (Byte by Byte)		40	200 <sup>(3)</sup>	S
Chip Program (Word by Word)		20	100 <sup>(3)</sup>	S
Chip Program (Quadruple Byte or Double Word)		10	100 <sup>(3)</sup>	S
Program/Erase Cycles (per Block)	100,000			cycles
Data Retention	20			years

Note: 1. Typical values measured at room temperature and nominal voltages.

2. Sampled, but not 100% tested.

3. Maximum value measured at worst case conditions for both temperature and V<sub>CC</sub> after 100,00 program/erase cycles.

4. Maximum value measured at worst case conditions for both temperature and  $V_{CC}$ .

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## STATUS REGISTER

The M29DW323D has two Status Registers, one for each bank. The Status Registers provide information on the current or previous Program or Erase operations executed in each bank. The various bits convey information and errors on the operation. Bus Read operations from any address within the Bank, always read the Status Register during Program and Erase operations. It is also read during Erase Suspend when an address within a block being erased is accessed.

The bits in the Status Register are summarized in Table 8, Status Register Bits.

**Data Polling Bit (DQ7).** The Data Polling Bit can be used to identify whether the Program/Erase Controller has successfully completed its operation or if it has responded to an Erase Suspend. The Data Polling Bit is output on DQ7 when the Status Register is read.

During Program operations the Data Polling Bit outputs the complement of the bit being programmed to DQ7. After successful completion of the Program operation the memory returns to Read mode and Bus Read operations from the address just programmed output DQ7, not its complement.

During Erase operations the Data Polling Bit outputs '0', the complement of the erased state of DQ7. After successful completion of the Erase operation the memory returns to Read Mode.

In Erase Suspend mode the Data Polling Bit will output a '1' during a Bus Read operation within a block being erased. The Data Polling Bit will change from a '0' to a '1' when the Program/Erase Controller has suspended the Erase operation.

Figure 8, Data Polling Flowchart, gives an example of how to use the Data Polling Bit. A Valid Address is the address being programmed or an address within the block being erased.

**Toggle Bit (DQ6).** The Toggle Bit can be used to identify whether the Program/Erase Controller has successfully completed its operation or if it has responded to an Erase Suspend. The Toggle Bit is output on DQ6 when the Status Register is read.

During Program and Erase operations the Toggle Bit changes from '0' to '1' to '0', etc., with successive Bus Read operations at any address. After successful completion of the operation the memory returns to Read mode.

During Erase Suspend mode the Toggle Bit will output when addressing a cell within a block being erased. The Toggle Bit will stop toggling when the Program/Erase Controller has suspended the Erase operation. Figure 9, Data Toggle Flowchart, gives an example of how to use the Data Toggle Bit.

**Error Bit (DQ5).** The Error Bit can be used to identify errors detected by the Program/Erase Controller. The Error Bit is set to '1' when a Program, Block Erase or Chip Erase operation fails to write the correct data to the memory. If the Error Bit is set a Read/Reset command must be issued before other commands are issued. The Error bit is output on DQ5 when the Status Register is read.

Note that the Program command cannot change a bit set to '0' back to '1' and attempting to do so will set DQ5 to '1'. A Bus Read operation to that address will show the bit is still '0'. One of the Erase commands must be used to set all the bits in a block or in the whole memory from '0' to '1'.

**Erase Timer Bit (DQ3).** The Erase Timer Bit can be used to identify the start of Program/Erase Controller operation during a Block Erase command. Once the Program/Erase Controller starts erasing the Erase Timer Bit is set to '1'. Before the Program/Erase Controller starts the Erase Timer Bit is set to '0' and additional blocks to be erased may be written to the Command Interface. The Erase Timer Bit is output on DQ3 when the Status Register is read.

Alternative Toggle Bit (DQ2). The Alternative Toggle Bit can be used to monitor the Program/ Erase controller during Erase operations. The Alternative Toggle Bit is output on DQ2 when the Status Register is read.

During Chip Erase and Block Erase operations the Toggle Bit changes from '0' to '1' to '0', etc., with successive Bus Read operations from addresses within the blocks being erased. A protected block is treated the same as a block not being erased. Once the operation completes the memory returns to Read mode.

During Erase Suspend the Alternative Toggle Bit changes from '0' to '1' to '0', etc. with successive Bus Read operations from addresses within the blocks being erased. Bus Read operations to addresses within blocks not being erased will output the memory cell data as if in Read mode.

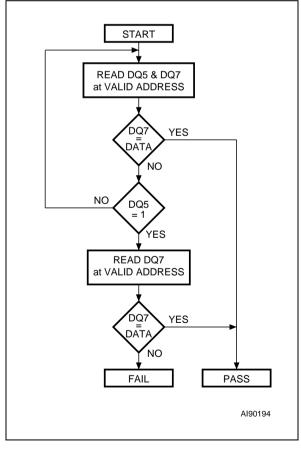
After an Erase operation that causes the Error Bit to be set the Alternative Toggle Bit can be used to identify which block or blocks have caused the error. The Alternative Toggle Bit changes from '0' to '1' to '0', etc. with successive Bus Read Operations from addresses within blocks that have not erased correctly. The Alternative Toggle Bit does not change if the addressed block has erased correctly.

Operation	Address	DQ7	DQ6	DQ5	DQ3	DQ2	RB
Program	Bank Address	DQ7	Toggle	0	_	-	0
Program During Erase Suspend	Bank Address	DQ7	Toggle	0	_	-	0
Program Error	Bank Address	DQ7	Toggle	1	_	-	0
Chip Erase	Any Address	0	Toggle	0	1	Toggle	0
Block Erase before	Erasing Block	0	Toggle	0	0	Toggle	0
timeout	Non-Erasing Block	0	Toggle	0	0	No Toggle	0
Diask France	Erasing Block	0	Toggle	0	1	Toggle	0
Block Erase	Non-Erasing Block	0	Toggle	0	1	No Toggle	0
Frees Sugnand	Erasing Block	1	No Toggle	0	_	Toggle	1
Erase Suspend	Non-Erasing Block		Data	read as no	ormal		1
Frees Freez	Good Block Address	0	Toggle	1	1	No Toggle	0
Erase Error	Faulty Block Address	0	Toggle	1	1	Toggle	0

#### **Table 8. Status Register Bits**

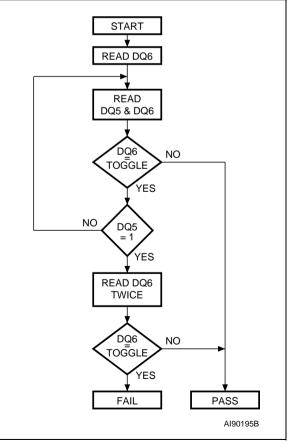
Note: Unspecified data bits should be ignored.

## Figure 8. Data Polling Flowchart



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# Figure 9. Data Toggle Flowchart



#### MAXIMUM RATING

Stressing the device above the rating listed in the Absolute Maximum Ratings table may cause permanent damage to the device. Exposure to Absolute Maximum Rating conditions for extended periods may affect device reliability. These are stress ratings only and operation of the device at these or any other conditions above those indicated in the Operating sections of this specification is not implied. Refer also to the STMicroelectronics SURE Program and other relevant quality documents.

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Symbol	Parameter	Min	Max	Unit
T <sub>BIAS</sub>	Temperature Under Bias	-50	125	°C
T <sub>STG</sub>	Storage Temperature	-65	150	°C
V <sub>IO</sub>	Input or Output Voltage <sup>(1,2)</sup>	-0.6	V <sub>CC</sub> +0.6	V
Vcc	Supply Voltage	-0.6	4	V
V <sub>ID</sub>	Identification Voltage	-0.6	13.5	V
V <sub>PP</sub> <sup>(3)</sup>	Program Voltage	-0.6	13.5	V

#### **Table 9. Absolute Maximum Ratings**

Note: 1. Minimum voltage may undershoot to -2V during transition and for less than 20ns during transitions.

2. Maximum voltage may overshoot to  $V_{CC}$  +2V during transition and for less than 20ns during transitions.

3. VPP must not remain at 12V for more than a total of 80hrs.

#### DC AND AC PARAMETERS

This section summarizes the operating measurement conditions, and the DC and AC characteristics of the device. The parameters in the DC and AC characteristics Tables that follow, are derived from tests performed under the Measurement Conditions summarized in Table 10, Operating and AC Measurement Conditions. Designers should check that the operating conditions in their circuit match the operating conditions when relying on the quoted parameters.

### Table 10. Operating and AC Measurement Conditions

Parameter	70		9	Unit	
	Min	Max	Min	Max	
V <sub>CC</sub> Supply Voltage	3.0	3.6	2.7	3.6	V
Ambient Operating Temperature	-40	85	-40	85	°C
Load Capacitance (CL)	3	30	30		pF
Input Rise and Fall Times		10	10 10		ns
Input Pulse Voltages	0 to V <sub>CC</sub>		0 to V <sub>CC</sub>		V
Input and Output Timing Ref. Voltages	V <sub>CC</sub> /2 V <sub>CC</sub> /2		<sub>C</sub> /2	V	

### Figure 10. AC Measurement I/O Waveform

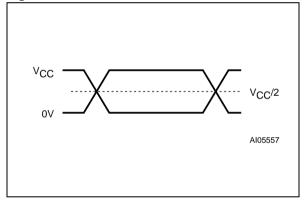
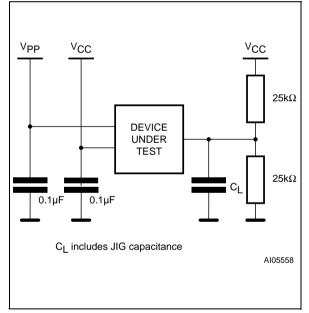


Figure 11. AC Measurement Load Circuit



#### Table 11. Device Capacitance

Symbol	ol Parameter Test Condition Mi		Min	Max	Unit
C <sub>IN</sub>	Input Capacitance	$V_{IN} = 0V$		6	pF
C <sub>OUT</sub>	Output Capacitance	V <sub>OUT</sub> = 0V		12	pF

Note: Sampled only, not 100% tested.

## **Table 12. DC Characteristics**

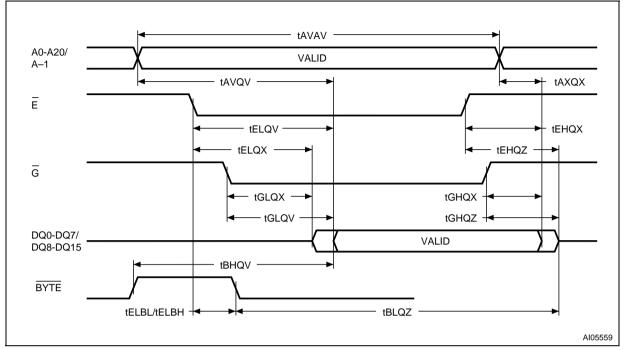
Symbol	Parameter	Test Condition		Min	Max	Unit
ILI	Input Leakage Current	$0V \le V_{IN}$	I ≤ V <sub>CC</sub>		±1	μA
I <sub>LO</sub>	Output Leakage Current	0V ≤ V <sub>OU</sub>	T ≤ V <sub>CC</sub>		±1	μA
I <sub>CC1</sub> <sup>(2)</sup>	Supply Current (Read)	$\overline{E} = V_{IL}, \overline{C}$ $f = 6N$			10	mA
I <sub>CC2</sub>	Supply Current (Standby)	$\overline{E} = V_{CC}$ $\overline{RP} = V_{CC}$			100	μA
I <sub>CC3</sub> <sup>(1,2)</sup>	Supply Current (Program/	Program/Erase V <sub>IL</sub> or V <sub>IH</sub>			20	mA
	Erase)	crase) Controller active	$V_{PP}/\overline{WP} = V_{PP}$		20	mA
VIL	Input Low Voltage			-0.5	0.8	V
VIH	Input High Voltage			0.7V <sub>CC</sub>	V <sub>CC</sub> +0.3	V
V <sub>PP</sub>	Voltage for V <sub>PP</sub> / <del>WP</del> Program Acceleration	V <sub>CC</sub> = 3.0V ±10%		11.5	12.5	V
Ipp	Current for V <sub>PP</sub> /WP Program Acceleration	V <sub>CC</sub> = 3.0V ±10%			15	mA
V <sub>OL</sub>	Output Low Voltage	I <sub>OL</sub> = 1.8mA			0.45	V
V <sub>OH</sub>	Output High Voltage	I <sub>OH</sub> = −100μA		V <sub>CC</sub> –0.4		V
VID	Identification Voltage			11.5	12.5	V
V <sub>LKO</sub>	Program/Erase Lockout Supply Voltage			1.8	2.3	V

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Note: 1. Sampled only, not 100% tested.

2. In Dual operations the Supply Current will be the sum of I<sub>CC1</sub>(read) and I<sub>CC3</sub> (program/erase).

# Figure 12. Read Mode AC Waveforms

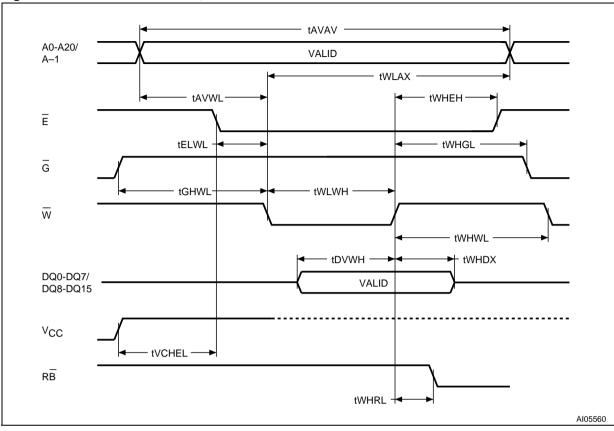


## Table 13. Read AC Characteristics

Cumbal	Alt	Parameter	Test Condition		M29DW323D		Unit
Symbol	Alt	Parameter			70 90		
t <sub>AVAV</sub>	t <sub>RC</sub>	Address Valid to Next Address Valid	$\overline{E} = V_{IL},$ $\overline{G} = V_{IL}$	Min	70	90	ns
tavqv	tACC	Address Valid to Output Valid	$\overline{E} = V_{IL},$ $\overline{G} = V_{IL}$	Max	70	90	ns
t <sub>ELQX</sub> <sup>(1)</sup>	t <sub>LZ</sub>	Chip Enable Low to Output Transition	$\overline{G} = V_{IL}$ Min		0	0	ns
t <sub>ELQV</sub>	t <sub>CE</sub>	Chip Enable Low to Output Valid	$\overline{G} = V_{IL}$ Max		70	90	ns
t <sub>GLQX</sub> <sup>(1)</sup>	t <sub>OLZ</sub>	Output Enable Low to Output Transition	Ē = V <sub>IL</sub> Min		0	0	ns
tGLQV	tOE	Output Enable Low to Output Valid	$\overline{E} = V_{IL}$	Max	30	35	ns
t <sub>EHQZ</sub> <sup>(1)</sup>	t <sub>HZ</sub>	Chip Enable High to Output Hi-Z	$\overline{G} = V_{IL}$ Max		25	30	ns
t <sub>GHQZ</sub> <sup>(1)</sup>	t <sub>DF</sub>	Output Enable High to Output Hi-Z	$\overline{E} = V_{IL}$	Max	25	30	ns
tehqx tghqx taxqx	t <sub>OH</sub>	Chip Enable, Output Enable or Address Transition to Output Transition	Min		0	0	ns
telbl telbh	telfl telfh	Chip Enable to BYTE Low or High	Max		5	5	ns
t <sub>BLQZ</sub>	t <sub>FLQZ</sub>	BYTE Low to Output Hi-Z	Мах		25	30	ns
t <sub>BHQV</sub>	t <sub>FHQV</sub>	BYTE High to Output Valid		Max	30	40	ns

Note: 1. Sampled only, not 100% tested.

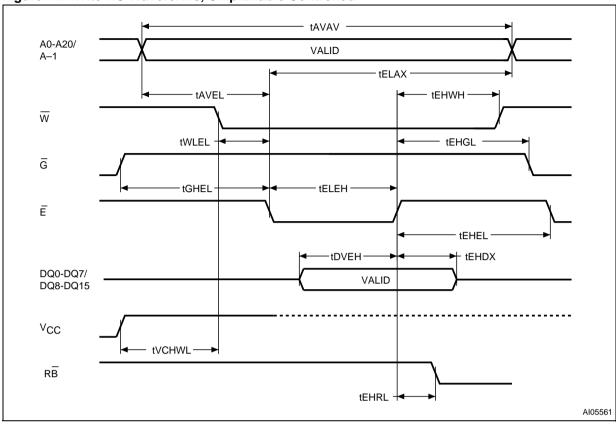
# 57



# Figure 13. Write AC Waveforms, Write Enable Controlled

Sumbal	A 14	Deremeter	M29D	M29DW323D		
Symbol	Alt	Parameter		70	90	Unit
t <sub>AVAV</sub>	t <sub>WC</sub>	Address Valid to Next Address Valid	Min	70	90	ns
tELWL	tcs	Chip Enable Low to Write Enable Low	Min	0	0	ns
t <sub>WLWH</sub>	t <sub>WP</sub>	Write Enable Low to Write Enable High	Min	45	50	ns
t <sub>DVWH</sub>	t <sub>DS</sub>	Input Valid to Write Enable High	Min	45	50	ns
t <sub>WHDX</sub>	t <sub>DH</sub>	Write Enable High to Input Transition	Min	0	0	ns
t <sub>WHEH</sub>	t <sub>CH</sub>	Write Enable High to Chip Enable High	Min	0	0	ns
twhwL	twph	Write Enable High to Write Enable Low	Min	30	30	ns
t <sub>AVWL</sub>	t <sub>AS</sub>	Address Valid to Write Enable Low	Min	0	0	ns
t <sub>WLAX</sub>	t <sub>AH</sub>	Write Enable Low to Address Transition	Min	45	50	ns
tGHWL		Output Enable High to Write Enable Low	Min	0	0	ns
t <sub>WHGL</sub>	t <sub>OEH</sub>	Write Enable High to Output Enable Low	Min	0	0	ns
t <sub>WHRL</sub> <sup>(1)</sup>	tBUSY	Program/Erase Valid to RB Low	Max	30	35	ns
<b>t</b> VCHEL	t <sub>VCS</sub>	V <sub>CC</sub> High to Chip Enable Low	Min	50	50	μs

Note: 1. Sampled only, not 100% tested.



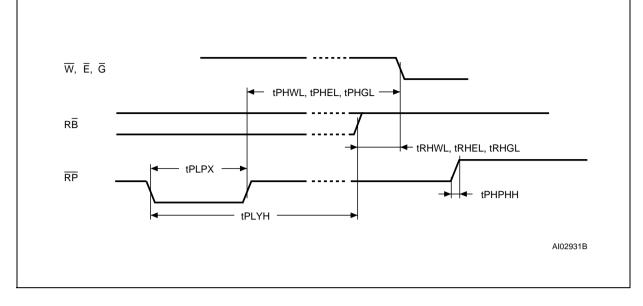
# Figure 14. Write AC Waveforms, Chip Enable Controlled

Table 15. Write	AC Characteristics,	Chip Enable	Controlled
14810 101 11110	/ • • • • • • • • • • • • • • • • • • •		•••••••

Sympol	A 14	Devemedar	M29DW323D		1	
Symbol	Alt	Parameter	70	90	Unit	
t <sub>AVAV</sub>	t <sub>WC</sub>	Address Valid to Next Address Valid	Min	70	90	ns
t <sub>WLEL</sub>	t <sub>WS</sub>	Write Enable Low to Chip Enable Low	Min	0	0	ns
tELEH	t <sub>CP</sub>	Chip Enable Low to Chip Enable High	Min	45	50	ns
t <sub>DVEH</sub>	t <sub>DS</sub>	Input Valid to Chip Enable High	Min	45	50	ns
t <sub>EHDX</sub>	t <sub>DH</sub>	Chip Enable High to Input Transition	Min	0	0	ns
tehwh	t <sub>WH</sub>	Chip Enable High to Write Enable High	Min	0	0	ns
t <sub>EHEL</sub>	t <sub>CPH</sub>	Chip Enable High to Chip Enable Low	Min	30	30	ns
tAVEL	t <sub>AS</sub>	Address Valid to Chip Enable Low	Min	0	0	ns
t <sub>ELAX</sub>	t <sub>AH</sub>	Chip Enable Low to Address Transition	Min	45	50	ns
t <sub>GHEL</sub>		Output Enable High Chip Enable Low	Min	0	0	ns
t <sub>EHGL</sub>	tOEH	Chip Enable High to Output Enable Low	Min	0	0	ns
t <sub>EHRL</sub> <sup>(1)</sup>	t <sub>BUSY</sub>	Program/Erase Valid to RB Low	Max	30	35	ns
t <sub>VCHWL</sub>	t <sub>VCS</sub>	V <sub>CC</sub> High to Write Enable Low Min		50	50	μs

Note: 1. Sampled only, not 100% tested.

## Figure 15. Reset/Block Temporary Unprotect AC Waveforms

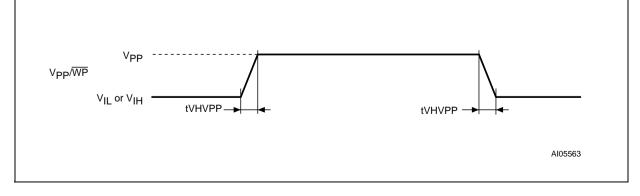


## Table 16. Reset/Block Temporary Unprotect AC Characteristics

Symbol	Alt	Parameter			M29DW323D		
Symbol					90	Unit	
t <sub>PHWL</sub> <sup>(1)</sup> t <sub>PHEL</sub> t <sub>PHGL</sub> <sup>(1)</sup>	t <sub>RH</sub>	RP High to Write Enable Low, Chip Enable Low, Output Enable Low	Min	50	50	ns	
t <sub>RHWL</sub> <sup>(1)</sup> t <sub>RHEL</sub> <sup>(1)</sup> t <sub>RHGL</sub> <sup>(1)</sup>	t <sub>RB</sub>	RB High to Write Enable Low, Chip Enable Low, Output Enable Low	Min	0	0	ns	
t <sub>PLPX</sub>	t <sub>RP</sub>	RP Pulse Width	Min	500	500	ns	
t <sub>PLYH</sub>	t <sub>READY</sub>	RP Low to Read Mode	Max	50	50	μs	
tphphh <sup>(1)</sup>	t <sub>VIDR</sub>	RP Rise Time to V <sub>ID</sub>	Min	500	500	ns	
t <sub>VHVPP</sub> <sup>(1)</sup>		V <sub>PP</sub> Rise and Fall Time	Min	250	250	ns	

Note: 1. Sampled only, not 100% tested.

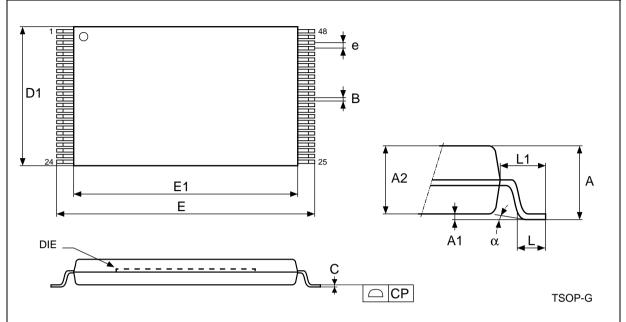
# Figure 16. Accelerated Program Timing Waveforms



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# PACKAGE MECHANICAL



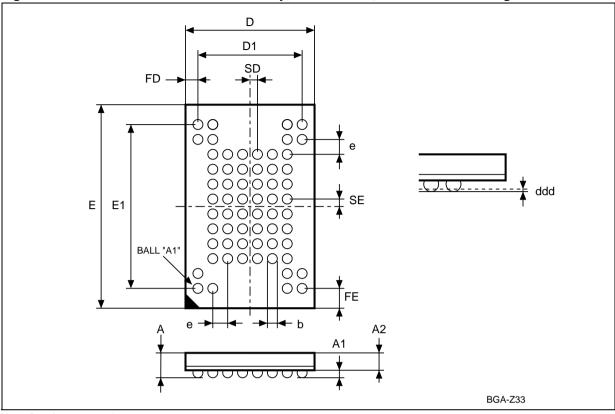


Note: Drawing not to scale.

# Table 17. TSOP48 Lead Plastic Thin Small Outline, 12x20 mm, Package Mechanical Data

Symbol		millimeters				
Symbol	Тур	Min	Max	Тур	Min	Max
А			1.200			0.0472
A1	0.100	0.050	0.150	0.0039	0.0020	0.0059
A2	1.000	0.950	1.050	0.0394	0.0374	0.0413
В	0.220	0.170	0.270	0.0087	0.0067	0.0106
С		0.100	0.210		0.0039	0.0083
CP			0.080			0.0031
D1	12.000	11.900	12.100	0.4724	0.4685	0.4764
E	20.000	19.800	20.200	0.7874	0.7795	0.7953
E1	18.400	18.300	18.500	0.7244	0.7205	0.7283
е	0.500	_	-	0.0197	-	-
L	0.600	0.500	0.700	0.0236	0.0197	0.0276
L1	0.800			0.0315		
α	3	0	5	3	0	5

# Figure 18. TFBGA63 7x11mm - 6x8 Ball Array, 0.8mm Pitch, Bottom View Package Outline

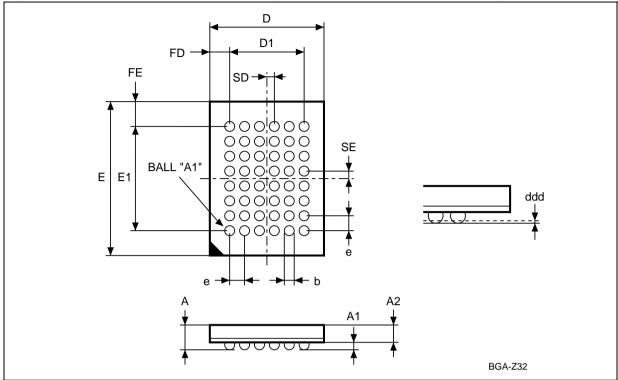


Note: Drawing not to scale.

Cumula al		millimeters				
Symbol	Тур	Min	Мах	Тур	Min	Мах
А			1.200			0.0472
A1		0.250			0.0098	
A2			0.900			0.0354
b		0.350	0.450		0.0138	0.0177
D	7.000	6.900	7.100	0.2756	0.2717	0.2795
D1	5.600	_	_	0.2205	-	-
ddd	_	_	0.100	_	-	0.0039
E	11.000	10.900	11.100	0.4331	0.4291	0.4370
E1	8.800	_	_	0.3465	-	-
е	0.800	-	_	0.0315	-	-
FD	0.700	-	-	0.0276	-	-
FE	1.100	-	-	0.0433	-	-
SD	0.400	-	-	0.0157	-	-
SE	0.400	-	_	0.0157	-	-

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Figure 19. TFBGA48 6x8mm - 6x8 Ball Array, 0.8mm Pitch, Bottom View Package Outline



Note: Drawing not to scale.

## Table 19. TFBGA48 6x8mm - 6x8 Ball Array, 0.8mm Pitch, Package Mechanical Data

Symbol	millimeters			inches		
	Тур	Min	Max	Тур	Min	Max
А			1.200			0.0472
A1		0.260			0.0102	
A2			0.900			0.0354
b		0.350	0.450		0.0138	0.0177
D	6.000	5.900	6.100	0.2362	0.2323	0.2402
D1	4.000	-	-	0.1575	_	-
ddd			0.100			0.0039
Е	8.000	7.900	8.100	0.3150	0.3110	0.3189
E1	5.600	-	-	0.2205	_	-
е	0.800	-	-	0.0315	_	-
FD	1.000	-	_	0.0394	_	-
FE	1.200	-	-	0.0472	-	-
SD	0.400	-	-	0.0157	-	-
SE	0.400	-	-	0.0157	-	-

## PART NUMBERING

## Table 20. Ordering Information Scheme

Example:	M29DW323DI	B 70 N 1 T
Device Type		
M29		
Architecture		
D = Dual Bank		
Operating Voltage		
$W = V_{CC} = 2.7 \text{ to } 3.6 \text{V}$		
Device Function		
323D = 32 Mbit (x8/x16), Boot Block, 1/4-3/4 partitionin	ng	
Array Matrix		
T = Top Boot		
B = Bottom Boot		
Speed		
70 = 70 ns		
90 = 90 ns		
Package		
N = TSOP48: 12 x 20 mm		
ZA = TFBGA63: 7 x 11mm, 0.80 mm pitch		
ZE = TFBGA48: 6 x 8mm, 0.8mm pitch		
Temperature Range		
1 = 0 to 70 °C		
6 = -40 to 85 °C		
Option		

Blank = Standard Packing T = Tape & Reel Packing E = Lead-free Package, Standard Packing F = Lead-free Package, Tape & Reel Packing

Note: This product is also available with the Extended Block factory locked. For further details and ordering information contact your nearest ST sales office.

Devices are shipped from the factory with the memory content bits erased to '1'.

For a list of available options (Speed, Package, etc...) or for further information on any aspect of this device, please contact the ST Sales Office nearest to you.

# APPENDIX A. BLOCK ADDRESSES

Bank	Block	(Kbytes/ Kwords)	Protection Block Group	(x8)	(x16)
	0	64/32	Protection Group	000000h-00FFFFh	000000h-07FFFh
	1	64/32		010000h-01FFFFh	008000h-0FFFFh
	2	64/32	Protection Group	020000h-02FFFFh	010000h-17FFFh
	3	64/32		030000h-03FFFFh	018000h-01FFFFh
	4	64/32	Protection Group	040000h-04FFFFh	020000h-027FFFh
	5	64/32		050000h-05FFFFh	028000h-02FFFFh
	6	64/32		060000h-06FFFFh	030000h-037FFFh
	7	64/32		070000h-07FFFFh	038000h-03FFFFh
	8	64/32		080000h-08FFFFh	040000h-047FFFh
	9	64/32	Drotoction Crown	090000h-09FFFFh	048000h-04FFFFh
	10	64/32	<ul> <li>Protection Group</li> </ul>	0A0000h-0AFFFFh	050000h-057FFFh
	11	64/32		0B0000h-0BFFFFh	058000h-05FFFFh
	12	64/32	Protection Group	0C0000h-0CFFFFh	060000h-067FFFh
	13	64/32		0D0000h-0DFFFFh	068000h-06FFFFh
	14	64/32		0E0000h-0EFFFFh	070000h-077FFFh
k B	15	64/32		0F0000h-0FFFFFh	078000h-07FFFFh
Bank	16	64/32		100000h-10FFFFh	080000h-087FFFh
	17	64/32	Brotaction Crown	110000h-11FFFFh	088000h-08FFFFh
	18	64/32	<ul> <li>Protection Group</li> </ul>	120000h-12FFFFh	090000h-097FFFh
	19	64/32	1	130000h-13FFFFh	098000h-09FFFFh
	20	64/32		140000h-14FFFFh	0A0000h-0A7FFFh
	21	64/32	Protection Group	150000h-15FFFFh	0A8000h-0AFFFFh
	22	64/32		160000h-16FFFFh	0B0000h-0B7FFFh
	23	64/32	1	170000h-17FFFFh	0B8000h-0BFFFFh
	24	64/32		180000h-18FFFFh	0C0000h-0C7FFFh
	25	64/32	Protection Group	190000h-19FFFFh	0C8000h-0CFFFFh
	26	64/32		1A0000h-1AFFFFh	0D0000h-0D7FFFh
	27	64/32		1B0000h-1BFFFFh	0D8000h-0DFFFFh
	28	64/32		1C0000h-1CFFFFh	0E0000h-0E7FFFh
	29	64/32	Protection Group	1D0000h-1DFFFFh	0E8000h-0EFFFFh
	30	64/32		1E0000h-1EFFFFh	0F0000h-0F7FFFh
	31	64/32		1F0000h-1FFFFFh	0F8000h-0FFFFh

Table 21. Top Boot Block Addresses, M29DW323DT

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# M29DW323DT, M29DW323DB

Bank	Block	(Kbytes/ Kwords)	Protection Block Group	(x8)	(x16)
	32	64/32		200000h-20FFFFh	100000h-107FFFh
	33	64/32		210000h-21FFFFh	108000h-10FFFFh
	34	64/32	<ul> <li>Protection Group</li> </ul>	220000h-22FFFFh	110000h-117FFFh
	35	64/32		230000h-23FFFFh	118000h-11FFFFh
	36	64/32		240000h-24FFFFh	120000h-127FFFh
	37	64/32	Protection Group	250000h-25FFFFh	128000h-12FFFFh
	38	64/32		260000h-26FFFFh	130000h-137FFFh
кВ	39	64/32		270000h-27FFFFh	138000h-13FFFFh
Bank	40	64/32		280000h-28FFFFh	140000h-147FFFh
	41	64/32		290000h-29FFFFh	148000h-14FFFFh
	42	64/32	<ul> <li>Protection Group</li> </ul>	2A0000h-2AFFFFh	150000h-157FFFh
	43	64/32		2B0000h-2BFFFFh	158000h-15FFFFh
	44	64/32	Protection Group	2C0000h-2CFFFFh	160000h-167FFFh
	45	64/32		2D0000h-2DFFFFh	168000h-16FFFFh
	46	64/32		2E0000h-2EFFFFh	170000h-177FFFh
	47	64/32		2F0000h-2FFFFFh	178000h-17FFFFh
	48	64/32	Protection Group	300000h-30FFFFh	180000h-187FFFh
	49	64/32		310000h-31FFFFh	188000h-18FFFFh
	50	64/32		320000h-32FFFFh	190000h-197FFFh
	51	64/32		330000h-33FFFFh	198000h-19FFFFh
	52	64/32		340000h-34FFFFh	1A0000h-1A7FFFh
	53	64/32	Protection Group	350000h-35FFFFh	1A8000h-1AFFFFh
4	54	64/32		360000h-36FFFFh	1B0000h-1B7FFFh
Bank A	55	64/32		370000h-37FFFFh	1B8000h-1BFFFFh
ä	56	64/32		380000h-38FFFFh	1C0000h-1C7FFFh
	57	64/32	Protection Group	390000h-39FFFFh	1C8000h-1CFFFFh
	58	64/32		3A0000h-3AFFFFh	1D0000h-1D7FFFh
	59	64/32	]	3B0000h-3BFFFFh	1D8000h-1DFFFFh
	60	64/32		3C0000h-3CFFFFh	1E0000h-1E7FFFh
	61	64/32	Protection Group	3D0000h-3DFFFFh	1E8000h-1EFFFFh
	62	64/32		3E0000h-3EFFFFh	1F0000h-1F7FFFh

Bank	Block	(Kbytes/ Kwords)	Protection Block Group	(x8)	(x16)
	63	8/4	Protection Group	3F0000h-3F1FFFh <sup>(1)</sup>	1F8000h-1F8FFFh <sup>(1)</sup>
	64	8/4	Protection Group	3F2000h-3F3FFFh <sup>(1)</sup>	1F9000h-1F9FFFh <sup>(1)</sup>
	65	8/4	Protection Group	3F4000h-3F5FFFh <sup>(1)</sup>	1FA000h–1FAFFFh <sup>(1)</sup>
k A	66	8/4	Protection Group	3F6000h-3F7FFFh <sup>(1)</sup>	1FB000h–1FBFFFh <sup>(1)</sup>
Bank	67	8/4	Protection Group	3F8000h-3F9FFFh <sup>(1)</sup>	1FC000h-1FCFFFh <sup>(1)</sup>
	68	8/4	Protection Group	3FA000h-3FBFFFh <sup>(1)</sup>	1FD000h–1FDFFFh <sup>(1)</sup>
	69	8/4	Protection Group	3FC000h-3FDFFFh <sup>(1)</sup>	1FE000h–1FEFFFh <sup>(1)</sup>
	70	8/4	Protection Group	3FE000h-3FFFFFh <sup>(1)</sup>	1FF000h–1FFFFFh <sup>(1)</sup>

Note: 1. Used as the Extended Block Addresses in Extended Block mode.

# Table 22. Bottom Boot Block Addresses, M29DW323DB

Bank	Block	(Kbytes/ Kwords)	Protection Block Group	(x8)	(x16)
	0	8/4	Protection Group	000000h-001FFFh <sup>(1)</sup>	000000h-000FFFh <sup>(1)</sup>
	1	8/4	Protection Group	002000h-003FFFh <sup>(1)</sup>	001000h–001FFFh <sup>(1)</sup>
	2	8/4	Protection Group	004000h-005FFFh <sup>(1)</sup>	002000h–002FFFh <sup>(1)</sup>
	3	8/4	Protection Group	006000h-007FFFh <sup>(1)</sup>	003000h-003FFFh <sup>(1)</sup>
	4	8/4	Protection Group	008000h-009FFFh <sup>(1)</sup>	004000h-004FFFh <sup>(1)</sup>
	5	8/4	Protection Group	00A000h-00BFFFh <sup>(1)</sup>	005000h-005FFFh <sup>(1)</sup>
	6	8/4	Protection Group	00C000h-00DFFFh <sup>(1)</sup>	006000h-006FFFh <sup>(1)</sup>
	7	8/4	Protection Group	00E000h-00FFFFh <sup>(1)</sup>	007000h–007FFFh <sup>(1)</sup>
	8	64/32		010000h-01FFFFh	008000h-00FFFFh
	9	64/32	Protection Group	020000h-02FFFFh	010000h-017FFFh
kΑ	10	64/32		030000h-03FFFFh	018000h-01FFFFh
Bank A	11	64/32	Protection Group	040000h-04FFFFh	020000h-027FFFh
	12	64/32		050000h-05FFFFh	028000h-02FFFFh
	13	64/32		060000h-06FFFFh	030000h-037FFFh
	14	64/32		070000h-07FFFFh	038000h-03FFFFh
	15	64/32		080000h-08FFFFh	040000h-047FFFh
	16	64/32	Protection Group	090000h-09FFFFh	048000h-04FFFFh
	17	64/32		0A0000h-0AFFFFh	050000h-057FFFh
	18	64/32		0B0000h-0BFFFFh	058000h-05FFFFh
	19	64/32		0C0000h-0CFFFFh	060000h-067FFFh
	20	64/32	Drotoction Crown	0D0000h-0DFFFFh	068000h-06FFFFh
	21	64/32	Protection Group	0E0000h-0EFFFFh	070000h-077FFFh
	22	64/32		0F0000h-0FFFFFh	078000h-07FFFFh
	23	64/32		100000h-10FFFFh	080000h-087FFFh
	24	64/32	Protection Crown	110000h-11FFFFh	088000h-08FFFFh
	25	64/32	Protection Group	120000h-12FFFFh	090000h-097FFFh
ы Ц	26	64/32	] [	130000h-13FFFFh	098000h-09FFFFh
Bank B	27	64/32		140000h-14FFFFh	0A0000h-0A7FFFh
	28	64/32	Protection Group	150000h-15FFFFh	0A8000h-0AFFFFh
·	29	64/32		160000h-16FFFFh	0B0000h-0B7FFFh
	30	64/32	]	170000h-17FFFFh	0B8000h-0BFFFFh

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Bank	Block	(Kbytes/ Kwords)	Protection Block Group	(x8)	(x16)
	31	64/32		180000h-18FFFFh	0C0000h-0C7FFFh
	32	64/32	Drata etia a Casura	190000h-19FFFFh	0C8000h-0CFFFFh
	33	64/32	<ul> <li>Protection Group</li> </ul>	1A0000h-1AFFFFh	0D0000h-0D7FFFh
	34	64/32		1B0000h-1BFFFFh	0D8000h-0DFFFFh
	35	64/32		1C0000h-1CFFFFh	0E0000h-0E7FFFh
	36	64/32	Protection Group	1D0000h-1DFFFFh	0E8000h-0EFFFFh
	37	64/32	- Protection Group	1E0000h-1EFFFFh	0F0000h-0F7FFFh
	38	64/32		1F0000h-1FFFFFh	0F8000h-0FFFFFh
	39	64/32		200000h-20FFFFh	100000h-107FFFh
	40	64/32	Protection Group	210000h-21FFFFh	108000h-10FFFFh
	41	64/32		220000h-22FFFFh	110000h-117FFFh
	42	64/32		230000h-23FFFFh	118000h-11FFFFh
	43	64/32		240000h-24FFFFh	120000h-127FFFh
	44	64/32	Protection Group	250000h-25FFFFh	128000h-12FFFFh
	45	64/32		260000h-26FFFFh	130000h-137FFFh
к В	46	64/32	1	270000h-27FFFFh	138000h-13FFFFh
Bank	47	64/32		280000h-28FFFFh	140000h-147FFFh
	48	64/32	Protection Group	290000h-29FFFFh	148000h-14FFFFh
	49	64/32		2A0000h-2AFFFFh	150000h-157FFFh
	50	64/32		2B0000h-2BFFFFh	158000h-15FFFFh
	51	64/32		2C0000h-2CFFFFh	160000h-167FFFh
	52	64/32	Protection Group	2D0000h-2DFFFFh	168000h-16FFFFh
	53	64/32	Frotection Group	2E0000h-2EFFFFh	170000h-177FFFh
	54	64/32		2F0000h-2FFFFFh	178000h-17FFFFh
	55	64/32		300000h-30FFFFh	180000h–187FFFh
	56	64/32	Protection Group	310000h-31FFFFh	188000h-18FFFFh
	57	64/32		320000h-32FFFFh	190000h–197FFFh
	58	64/32	<u> </u>	330000h-33FFFFh	198000h-19FFFFh
	59	64/32		340000h-34FFFFh	1A0000h-1A7FFFh
	60	64/32	Protection Group	350000h-35FFFFh	1A8000h–1AFFFFh
	61	64/32		360000h-36FFFFh	1B0000h-1B7FFFh
	62	64/32		370000h-37FFFFh	1B8000h–1BFFFFh

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# M29DW323DT, M29DW323DB

Bank	Block	(Kbytes/ Kwords)	Protection Block Group	(x8)	(x16)
	63	64/32		380000h-38FFFFh	1C0000h-1C7FFFh
	64	64/32	Protection Group Protection Group	390000h-39FFFFh	1C8000h-1CFFFFh
	65	64/32		3A0000h-3AFFFFh	1D0000h-1D7FFFh
ъ В	66	64/32		3B0000h-3BFFFFh	1D8000h-1DFFFFh
Bank	67	64/32		3C0000h-3CFFFFh	1E0000h-1E7FFFh
	68	64/32		3D0000h-3DFFFFh	1E8000h-1EFFFFh
	69	64/32		3E0000h-3EFFFFh	1F0000h-1F7FFFh
	70	64/32	Protection Group	3F0000h-3FFFFFh	1F8000h–1FFFFFh

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Note: 1. Used as the Extended Block Addresses in Extended Block mode.

## APPENDIX B. COMMON FLASH INTERFACE (CFI)

The Common Flash Interface is a JEDEC approved, standardized data structure that can be read from the Flash memory device. It allows a system software to query the device to determine various electrical and timing parameters, density information and functions supported by the memory. The system can interface easily with the device, enabling the software to upgrade itself when necessary.

When the CFI Query Command is issued the device enters CFI Query mode and the data structure

is read from the memory. Tables 23, 24, 25, 26, 27 and 28 show the addresses used to retrieve the data.

The CFI data structure also contains a security area where a 64 bit unique security number is written (see Table 28, Security Code area). This area can be accessed only in Read mode by the final user. It is impossible to change the security number after it has been written by ST.

Add	ress	Sub-section Name	Description	
x16	x8	Sub-section Name	Description	
10h	20h	CFI Query Identification String	Command set ID and algorithm data offset	
1Bh	36h	System Interface Information	Device timing & voltage information	
27h	4Eh	Device Geometry Definition	Flash device layout	
40h	80h	Primary Algorithm-specific Extended Query table	Additional information specific to the Primary Algorithm (optional)	
61h	C2h	Security Code Area	64 bit unique device number	

#### Table 23. Query Structure Overview

Note: Query data are always presented on the lowest order data outputs.

### Table 24. CFI Query Identification String

Add	Address		Description	Value
x16	x8	Dala	Description	value
10h	20h	0051h		"Q"
11h	22h	0052h	Query Unique ASCII String "QRY"	"R"
12h	24h	0059h		"Y"
13h	26h	0002h	Primary Algorithm Command Set and Control Interface ID code 16 bit	AMD
14h	28h	0000h	ID code defining a specific algorithm	Compatible
15h	2Ah	0040h		
16h	2Ch	0000h	Address for Primary Algorithm extended Query table (see Table 27)	P = 40h
17h	2Eh	0000h	Alternate Vendor Command Set and Control Interface ID Code second	NA
18h	30h	0000h	vendor - specified algorithm supported	INA
19h	32h	0000h	Address for Alternate Algorithm extended Query table	NA
1Ah	34h	0000h		INA

Note: Query data are always presented on the lowest order data outputs (DQ7-DQ0) only. DQ8-DQ15 are '0'.

# Table 25. CFI Query System Interface Information

Add	Address		Description	Value
x16	x8	Data	Description	value
1Bh	36h	0027h	V <sub>CC</sub> Logic Supply Minimum Program/Erase voltage bit 7 to 4 BCD value in volts bit 3 to 0 BCD value in 100 mV	2.7V
1Ch	38h	0036h	V <sub>CC</sub> Logic Supply Maximum Program/Erase voltagebit 7 to 4BCD value in voltsbit 3 to 0BCD value in 100 mV	3.6V
1Dh	3Ah	00B5h	V <sub>PP</sub> [Programming] Supply Minimum Program/Erase voltage bit 7 to 4 HEX value in volts bit 3 to 0 BCD value in 100 mV	11.5V
1Eh	3Ch	00C5h	VPP [Programming] Supply Maximum Program/Erase voltage         bit 7 to 4       HEX value in volts         bit 3 to 0       BCD value in 100 mV	12.5V
1Fh	3Eh	0004h	Typical timeout per single byte/word program = $2^{n} \mu s$	16µs
20h	40h	0000h	Typical timeout for minimum size write buffer program = $2^{n} \mu s$	NA
21h	42h	000Ah	Typical timeout per individual block erase = 2 <sup>n</sup> ms	1s
22h	44h	0000h	Typical timeout for full chip erase = 2 <sup>n</sup> ms	NA
23h	46h	0004h	Maximum timeout for byte/word program = 2 <sup>n</sup> times typical	256 µs
24h	48h	0000h	Maximum timeout for write buffer program = 2 <sup>n</sup> times typical	NA
25h	4Ah	0003h	Maximum timeout per individual block erase = 2 <sup>n</sup> times typical	
26h	4Ch	0000h	Maximum timeout for chip erase = $2^n$ times typical	NA

## Table 26. Device Geometry Definition

Ado	Address		Data Description	
x16	x8	Dala	Description	Value
27h	4Eh	0016h	Device Size = 2 <sup>n</sup> in number of bytes	4 MByte
28h	50h	0002h	Flash Device Interface Code description	x8, x16
29h	52h	0000h		Async.
2Ah 2Bh	54h 56h	0000h 0000h	Maximum number of bytes in multi-byte program or page = 2 <sup>n</sup>	NA
2Ch	58h	0002h	Number of Erase Block Regions. It specifies the number of regions containing contiguous Erase Blocks of the same size.	2
2Dh	5Ah	0007h	Region 1 Information	8
2Eh	5Ch	0000h	Number of identical size erase block = 0007h+1	
2Fh	5Eh	0020h	Region 1 Information	8Kbyte
30h	60h	0000h	Block size in Region 1 = 0020h * 256 byte	
31h	62h	003Eh	Region 2 Information	63
32h	64h	0000h	Number of identical size erase block = 003Eh+1	
33h	66h	0000h	Region 2 Information	64Kbyte
34h	68h	0001h	Block size in Region 2 = 0100h * 256 byte	

Note: The region information contained in addresses 2Dh to 34h (or 5Ah to 68h) is correct for the M29DW323DB. For the M29DW323DT the regions must be reversed.

Address		Data	Description	
x16	x8	Dala	Description	
40h	80h	0050h		"P"
41h	82h	0052h	Primary Algorithm extended Query table unique ASCII string "PRI"	"R"
42h	84h	0049h		" "
43h	86h	0031h	Major version number, ASCII	"1"
44h	88h	0030h	Minor version number, ASCII	"0"
45h	8Ah	0000h	Address Sensitive Unlock (bits 1 to 0) 00 = required, 01= not required Silicon Revision Number (bits 7 to 2)	Yes
46h	8Ch	0002h	Erase Suspend 00 = not supported, 01 = Read only, 02 = Read and Write	2
47h	8Eh	0001h	Block Protection 00 = not supported, x = number of blocks in per group	1
48h	90h	0001h	Temporary Block Unprotect 00 = not supported, 01 = supported	Yes
49h	92h	0004h	Block Protect /Unprotect 04 = M29W400B	
4Ah	94h	0030h	Simultaneous Operations, x = number of blocks in Bank B	48
4Bh	96h	0000h	Burst Mode, 00 = not supported, 01 = supported	No
4Ch	98h	0000h	Page Mode, 00 = not supported, 01 = 4 page word, 02 = 8 page word	No
4Dh	9Ah	00B5h	V <sub>PP</sub> Supply Minimum Program/Erase voltage bit 7 to 4 HEX value in volts bit 3 to 0 BCD value in 100 mV	11.5V
4Eh	9Ch	00C5h	V <sub>PP</sub> Supply Maximum Program/Erase voltage bit 7 to 4 HEX value in volts bit 3 to 0 BCD value in 100 mV	
4Fh	9Eh	000xh	Top/Bottom Boot Block Flag 02h = Bottom Boot device, 03h = Top Boot device	_

# Table 27. Primary Algorithm-Specific Extended Query Table

# Table 28. Security Code Area

Ade	Address		Description		
x16	x8	Data	Description		
61h	C3h, C2h	XXXX			
62h	C5h, C4h	XXXX	C4 hitu unique device number		
63h	C7h, C6h	XXXX	64 bit: unique device number		
64h	C9h, C8h	XXXX			

# APPENDIX C. EXTENDED MEMORY BLOCK

The M29DW323D has an extra block, the Extended Block, that can be accessed using a dedicated command.

This Extended Block is 32 KWords in x16 mode and 64 KBytes in x8 mode. It is used as a security block (to provide a permanent security identification number) or to store additional information.

The Extended Block is either Factory Locked or Customer Lockable, its status is indicated by bit DQ7. This bit is permanently set to either '1' or '0' at the factory and cannot be changed. When set to '1', it indicates that the device is factory locked and the Extended Block is protected. When set to '0', it indicates that the device is customer lockable and the Extended Block is unprotected. Bit DQ7 being permanently locked to either '1' or '0' is another security feature which ensures that a customer lockable device cannot be used instead of a factory locked one.

Bit DQ7 is the most significant bit in the Extended Block Verify Code and a specific procedure must be followed to read it. See "Extended Memory Block Verify Code" in Tables 3 and 4, Bus Operations, BYTE =  $V_{IL}$  and Bus Operations, BYTE =  $V_{IH}$ , respectively, for details of how to read bit DQ7.

The Extended Block can only be accessed when the device is in Extended Block mode. For details of how the Extended Block mode is entered and exited, refer to the Enter Extended Block Command and Exit Extended Block Command paragraphs, and to Tables 5 and 6, "Commands, 16-bit mode, BYTE =  $V_{IH}$ " and "Commands, 8-bit mode, BYTE =  $V_{IL}$ ", respectively.

## Factory Locked Extended Block

In devices where the Extended Block is factory locked, the Security Identification Number is written to the Extended Block address space (see Table 29, Extended Block Address and Data) in the factory. The DQ7 bit is set to '1' and the Extended Block cannot be unprotected.

#### **Customer Lockable Extended Block**

A device where the Extended Block is customer lockable is delivered with the DQ7 bit set to '0' and the Extended Block unprotected. It is up to the customer to program and protect the Extended Block but care must be taken because the protection of the Extended Block is not reversible.

There are two ways of protecting the Extended Block:

- Issue the Enter Extended Block command to place the device in Extended Block mode, then use the In-System Technique (refer to Appendix D, In-System Technique and to the corresponding flowcharts, Figures 22 and 23, for a detailed explanation of the technique).
- Issue the Enter Extended Block command to place the device in Extended Block mode, then use the Programmer Technique (refer to Appendix D, Programmer Technique and to the corresponding flowcharts, Figures 20 and 21, for a detailed explanation of the technique).

Once the Extended Block is programmed and protected, the Exit Extended Block command must be issued to exit the Extended Block mode and return the device to Read mode.

Device	Addr	ess <sup>(1)</sup>	Data		
Device	x8	x16	Factory Locked	Customer Lockable	
M29DW323DT	3F0000h-3F000Fh	1F8000h-1F8007h	Security Identification Number	Determined by Customer	
	3F0010h-3FFFFFh	1F8008h-1FFFFFh	Unavailable	Customer	
M29DW323DB	000000h-00000Fh	000000h-000007h	Security Identification Number	Determined by Customer	
	000010h-00FFFFh	000008h-007FFFh	Unavailable	Customer	

#### Table 29. Extended Block Address and Data

Note: 1. See Tables 21 and 22, Top and Bottom Boot Block Addresses.

## APPENDIX D. BLOCK PROTECTION

Block protection can be used to prevent any operation from modifying the data stored in the memory. The blocks are protected in groups, refer to Appendix A, Tables 21 and 22 for details of the Protection Groups. Once protected, Program and Erase operations within the protected group fail to change the data.

There are three techniques that can be used to control Block Protection, these are the Programmer technique, the In-System technique and Temporary Unprotection. Temporary Unprotection is controlled by the Reset/Block Temporary Unprotection pin, RP; this is described in the Signal Descriptions section.

#### **Programmer Technique**

The Programmer technique uses high ( $V_{ID}$ ) voltage levels on some of the bus pins. These cannot be achieved using a standard microprocessor bus, therefore the technique is recommended only for use in Programming Equipment.

To protect a group of blocks follow the flowchart in Figure 20, Programmer Equipment Block Protect Flowchart. To unprotect the whole chip it is necessary to protect all of the groups first, then all groups can be unprotected at the same time. To unprotect the chip follow Figure 21, Programmer Equipment Chip Unprotect Flowchart. Table 30, Programmer Technique Bus Operations, gives a summary of each operation. The timing on these flowcharts is critical. Care should be taken to ensure that, where a pause is specified, it is followed as closely as possible. Do not abort the procedure before reaching the end. Chip Unprotect can take several seconds and a user message should be provided to show that the operation is progressing.

#### In-System Technique

The In-System technique requires a high voltage level on the Reset/Blocks Temporary Unprotect pin,  $\overline{RP}$ . This can be achieved without violating the maximum ratings of the components on the micro-processor bus, therefore this technique is suitable for use after the memory has been fitted to the system.

To protect a group of blocks follow the flowchart in Figure 22, In-System Block Protect Flowchart. To unprotect the whole chip it is necessary to protect all of the groups first, then all the groups can be unprotected at the same time. To unprotect the chip follow Figure 23, In-System Chip Unprotect Flowchart.

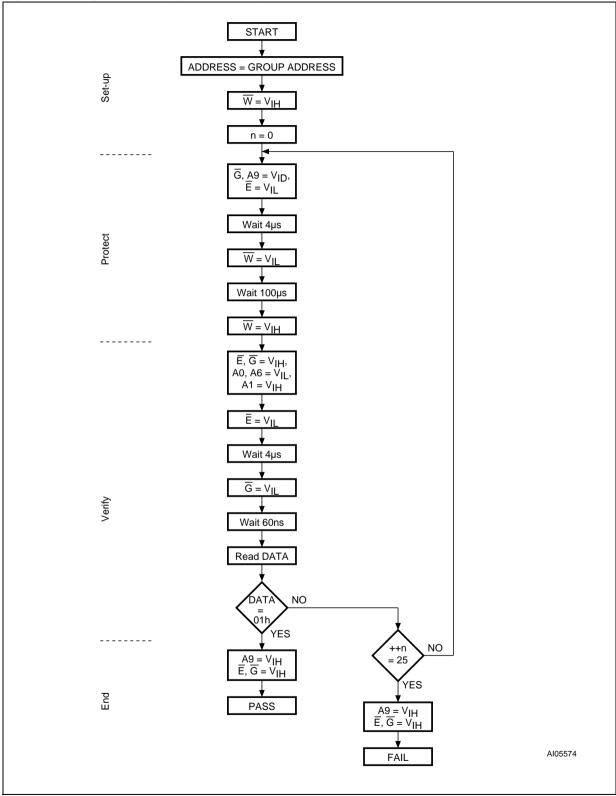
The timing on these flowcharts is critical. Care should be taken to ensure that, where a pause is specified, it is followed as closely as possible. Do not allow the microprocessor to service interrupts that will upset the timing and do not abort the procedure before reaching the end. Chip Unprotect can take several seconds and a user message should be provided to show that the operation is progressing.

Operation	Ē	G	W	Address Inputs A0-A20	Data Inputs/Outputs DQ15A–1, DQ14-DQ0
Block (Group) Protect <sup>(1)</sup>	VIL	V <sub>ID</sub>	VIL Pulse	A9 = V <sub>ID</sub> , A12-A20 Block Address Others = X	Х
Chip Unprotect	V <sub>ID</sub>	V <sub>ID</sub>	VIL Pulse	$\begin{array}{l} A9 = V_{ID},  A12 = V_{IH},  A15 = V_{IH} \\ Others = X \end{array}$	х
Block (Group) Protection Verify	VIL	VIL	VIH	$\begin{array}{l} A0 = V_{IL},  A1 = V_{IH},  A6 = V_{IL},  A9 = V_{ID}, \\ A12\text{-}A20 \; Block \; Address \\ Others = X \end{array}$	Pass = XX01h Retry = XX00h
Block (Group) Unprotection Verify	VIL	VIL	VIH	$\begin{array}{l} A0 = V_{IL}, A1 = V_{IH}, A6 = V_{IH}, A9 = V_{ID}, \\ A12\text{-}A20 \; Block \; Address \\ & \text{Others} = X \end{array}$	Retry = XX01h Pass = XX00h

## Table 30. Programmer Technique Bus Operations, $\overline{\text{BYTE}} = V_{\text{IH}}$ or $V_{\text{IL}}$

Note: 1. Block Protection Groups are shown in Appendix A, Tables 21 and 22.

### Figure 20. Programmer Equipment Group Protect Flowchart



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Note: Block Protection Groups are shown in Appendix D, Tables 21 and 22.

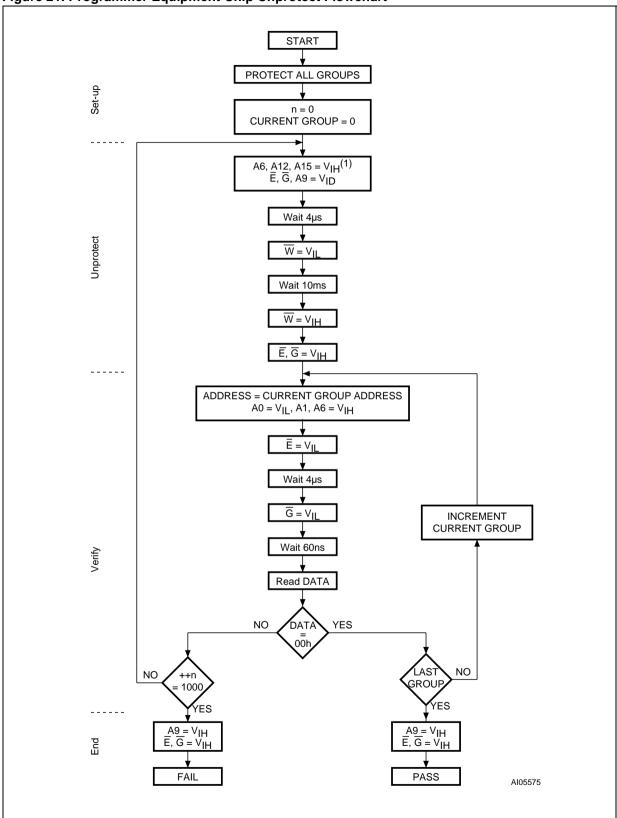
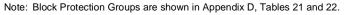
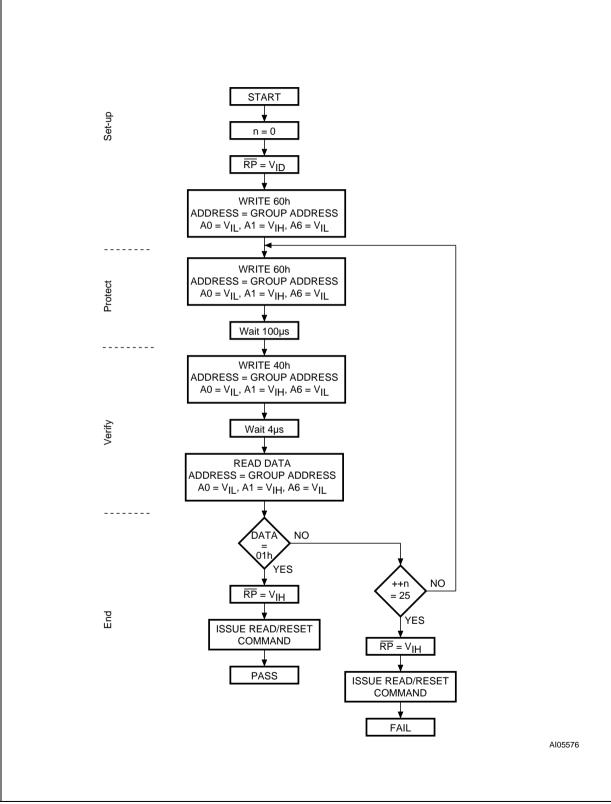


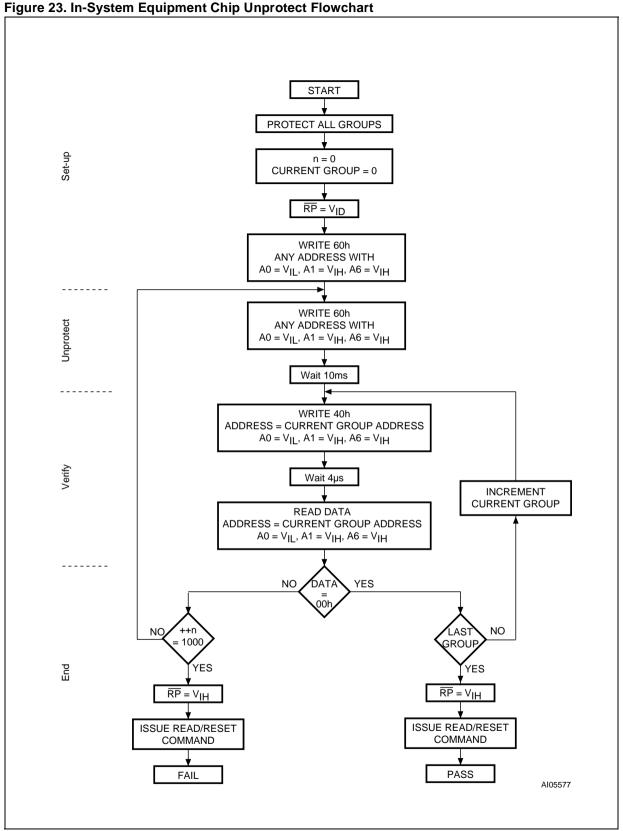
Figure 21. Programmer Equipment Chip Unprotect Flowchart



### Figure 22. In-System Equipment Group Protect Flowchart



Note: Block Protection Groups are shown in Appendix D, Tables 21 and 22.



Note: Block Protection Groups are shown in Appendix D, Tables 21 and 22.

# **REVISION HISTORY**

# Table 31. Document Revision History

Date	Version	Revision Details
20-Sep-2001	-01	First Issue (Target Specification)
26-Oct-2001	-02	Document expanded to full Product Preview
16-Jan-2002	-03	Corrections made in "Primary Algorithm-Specific Extended Query" Table in Appendix-B
19-Apr-2002	-04	Description of Ready/Busy signal clarified (and Figure 15 modified) Clarified allowable commands during block erase Clarified the mode the device returns to in the CFI Read Query command section tPLYH (time to reset device) re-specified.
24-Apr-2002	-05	Values for addresses 23h and 25h corrected in CFI Query System Interface Information table in Appendix B
19-Jul-2002	-06	When in Extended Block mode, the block at the boot block address can be used as OTP. Data Toggle Flow chart corrected. Document promoted from "Product Preview" to "Preliminary Data".
08-Apr-2003	6.1	Revision numbering modified: a minor revision will be indicated by incrementing the digit after the dot, and a major revision, by incrementing the digit before the dot (revision version 06 equals 6.0). Revision History moved to end of document. TFBGA48, 6 x 8mm, 0.80mm pitch package added. Identification Current I <sub>ID</sub> removed from Table 12, DC Characteristics. Erase Suspend Latency time and Data Retention parameters and notes added to Table 7, Program, Erase Times and Program, Erase Endurance Cycles. Appendix C, EXTENDED MEMORY BLOCK, added. Auto Select Command sued to read the Extended Memory Block. Extended Memory Block Verify Code row added to Tables 3 and 4, Bus Operations, BYTE = V <sub>IL</sub> and Bus Operations, BYTE = V <sub>IH</sub> . Bank Address modified in Auto Select Command. Chip Erase Address modified in Table 8, Status Register Bits. V <sub>SS</sub> pin connection to ground clarified. Note added to Table 20, Ordering Information Scheme.
07-May-2003	6.2	Table 17, TSOP48 Lead Plastic Thin Small Outline, 12x20 mm, Package Mechanical Data and Figure 17, TSOP48 Lead Plastic Thin Small Outline, 12x20 mm, Bottom View Package Outline, corrected.
25-Jun-2003	7.0	Document promoted from Preliminary Data to full Datasheet status. Packing option added to Table 20, Ordering Information Scheme.

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